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NAVAL POSTGRADUATE SCHOOL  
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THESIS

CONSTRUCTION AND TESTING OF AN 80C86 BASED  
COMMUNICATIONS CONTROLLER FOR THE PETITE  
AMATEUR NAVY SATELLITE (PANSAT)

by

Stephen M. Tobin

December, 1990

Thesis Advisor:

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Amateur Navy Satellite (PANSAT)

by

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Captain, United States Army  
B.S., United States Military Academy, 1980


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of the requirements for the degree of

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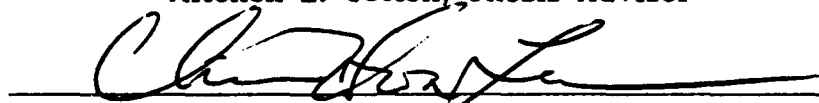
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## ABSTRACT

This thesis describes the testing of a prototype of a satellite computer communications controller, based on the 80C86 microprocessor, which is to be placed on the Petite Amateur Navy Satellite (PANSAT) for launch in 1993 on a two year mission. First, the background of the justification for PANSAT is described. PANSAT will serve primarily as an inexpensive store-and-forward orbiting "mailbox", and secondarily it will serve as a teaching and learning vehicle for NPS faculty and students. Then there are reviews of the requirements and design concepts involved in the initial paper design by a previous thesis student. A reliability analysis is done, validating the reliability of the design. Finally, concepts considered in the wire-wrapped prototype construction are explained, followed by an extensive description of initial circuit testing and development of various machine language circuit test programs.

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## I. INTRODUCTION

This thesis builds upon a principal previous thesis [Ref. 1]. That previous author's purpose was to derive an initial design for a small, inexpensive, reliable, on-board, satellite communications controller for the Petite Amateur Navy Satellite (PANSAT). Hence, much of the form and content of this introduction comes from that author's thesis.

### A. PURPOSE AND SCOPE OF THESIS

The purpose of this effort was to verify the utility and validity of the cited paper design of the on-board processor for the Petite Amateur Navy Satellite (PANSAT). The establishment of the processor requirements and the processor design were the subjects of that previous thesis [Ref. 1]. The requirement was to design and build a small, inexpensive, and reliable computer controller with enough memory and capability to act as a store-and-forward "mailbox" for amateur packet-radio messages using the AX.25 protocol. In addition, of course, the controller had to be able to withstand the extremes of radiation, heat, and cold in outer space. The design was a challenging task.

This current thesis is a continuation of only a portion of the required steps towards implementation of the actual flight-ready processor based on the initial design. This

effort concentrated on the building of a wire-wrapped breadboard prototype and the incremental testing of the hardware using relatively simple machine language programs. These programs were written to incrementally test some of the basic operations which will be required of the controller in its final flight-ready form. Correct operation of all the system's components within the system has been verified.

A 100 MHz dual-trace oscilloscope was the tool used to test for the presence of predicted signals. As the hardware and software of the system incrementally grew in complexity, it became increasingly difficult to verify correct circuit operation with just the oscilloscope, e.g., see the discussion of the third incremental test of the interrupt controller. Was the problem with the oscilloscope not being able to lock on the increasingly longer period, less stable signal, or was the problem with the program's complexity exceeding the circuit's capabilities? A better monitoring system will have to be constructed to carry on from this point. This possible (unlikely) circuit failure could indicate the necessity of some sort of redesign, assuming no flaws in the components or the prototype construction itself. Once a keyboard, monitor, and assembler/compiler are constructed for the system, the next step will be to find out if the system is in fact operating at the edge of its design parameters, and if so, what can be done about it.

## B. PANSAT BACKGROUND

The Petite Amateur Navy Satellite (PANSAT) is a small, simple, and inexpensive satellite currently being designed at the Naval Postgraduate School. It is a precursor to the NPS ORION satellite project.

### 1. PANSAT Concept

PANSAT is intended to be a space-based communications experiment that provides students with hands-on experience in satellite design and operations. It will accomplish three objectives. First, it will serve as an educational tool for NPS officer students, offering them experience in satellite design and operations. Second, it will provide world-wide digital communications using spread spectrum in the amateur band. Third, it will serve as a low-cost, space-based platform for small experiments. [Ref. 2:p. 2]

Additionally, it is an important milestone in achieving for the Space Systems Academic group its ultimate goal of producing the ORION satellite [Ref. 3]. It is a simpler and less capable satellite than ORION. Because PANSAT is less than half of ORION's size and is not attitude stabilized it can be produced for a fraction of the cost of the final version of ORION. Simplicity will help minimize the risks inherent in a first design. Simplicity will also result in reduced cost [Ref. 1:p. 1]. A tentative launch date has been set for 1993 [Ref. 4].

## 2. Mission and Objectives

The primary mission of PANSAT is to conduct a space-based communications experiment which will provide students with experience in design and operation of such a system. The desired implementation is a store-and-forward message system. In effect, the satellite would be a (delayed) transponder or mailbox. This would allow an authorized user to send a message to the satellite while the satellite was overhead. At a later time, another authorized user could retrieve the message. Outdated or retrieved messages could be (and would eventually have to be) deleted [Ref. 1:pp. 1-2].

In addition, several secondary missions are being considered if volumes and weights permit. These would probably require various analog or digital sensors which would amass various data, e.g., solar cell efficiency or degradation data. This telemetry data could then be periodically collected on-board by the computer and stored as messages. Various programs could be loaded into the satellite processor from the ground, and then tested. This could give NPS students, and others, experience in writing software for satellite control or experiments. One could also write monitor programs to monitor memory errors over time, or to monitor power usage by memory and processor components over time. This would allow students to evaluate the effects on memory circuits and/or semiconductor

components of exposure to increased radiation and a harsh environment [Ref. 1:p. 2].

### 3. PANSAT Design

The following are the working design constraints that impact on the processor system design.

#### a. Orbit

The first PANSAT is planned for launch from the space shuttle in a Get Away Special (GAS) canister or expendable launch vehicle. This constrains the satellite to a typical low earth orbit of approximately 480 km inclined at 28.5 degrees [Ref. 5:p. 2]. The actual orbit will depend on shuttle parameters of the particular mission that launches the PANSAT. Typical orbits have a 90 minute period. The orbit will also determine specific communication opportunities with the satellite. A typical orbit will provide only two or three, greater than ten-minute communications windows per day at the latitude of NPS for any particular ground station [Ref. 6:pp. 7-10].

#### b. Size

The Get Away Special canister size limits the physical size of the satellite. If a regular size canister is used, this limits satellite size to approximately 19 inches in diameter. Working within these limits, an octagonal cross section design is planned to maximize solar collector area. (See Figure 1.) The satellite volume reserved for the processor and its memory is also shown in

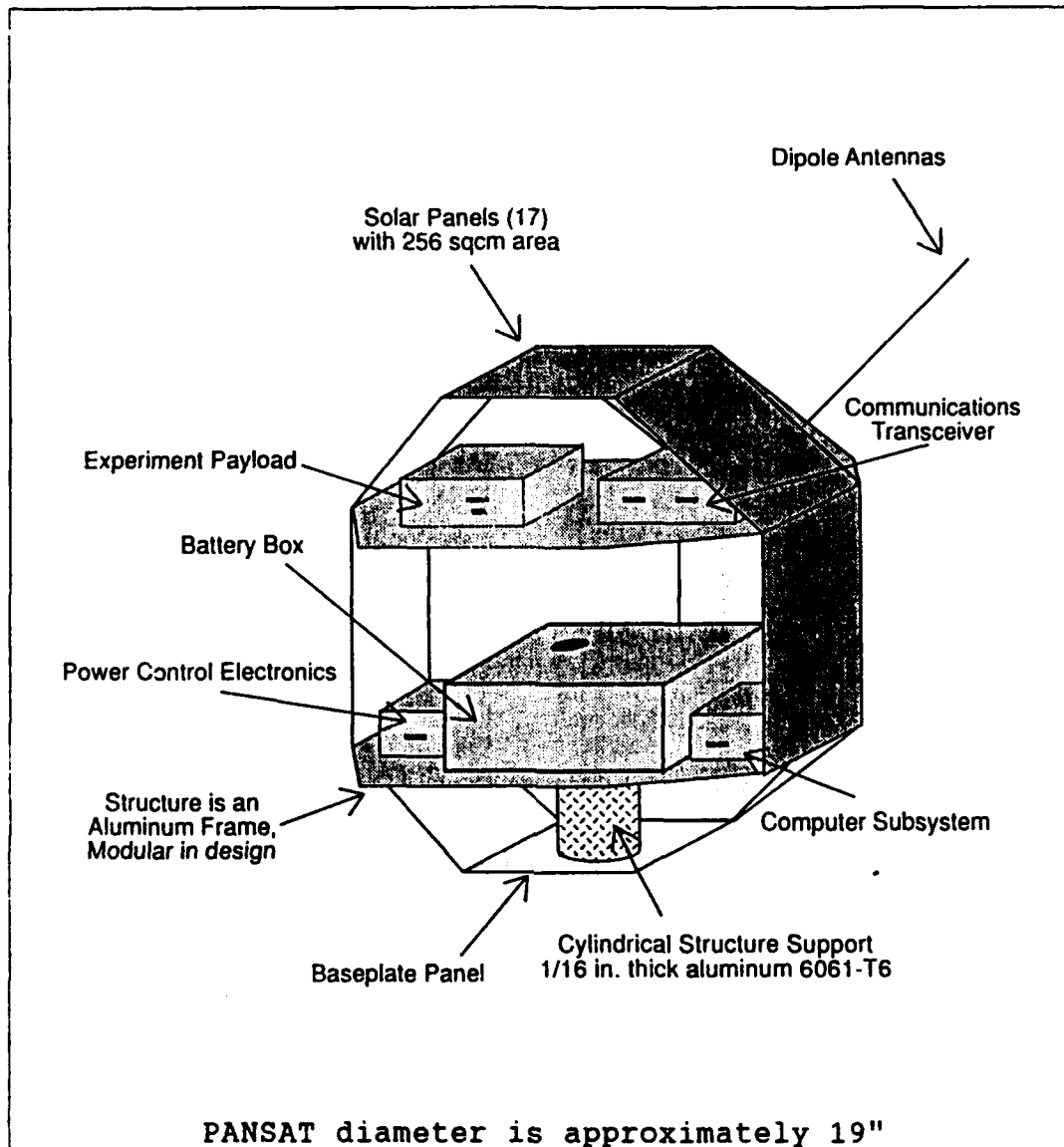


Figure 1. Pansat Size and Structure [Ref. 5]

the figure.

### c. Stabilization

The PANSAT will not be stabilized and will not have any station keeping ability. This means that the processor does not require the capability to monitor any attitude sensors or perform any stabilization calculations. Another



advantage to the lack of stabilization in relation to the processor is the potential to lessen the effect of solar heating on the daylight portion of the orbit which constitutes 61.20% of the total equatorial orbit based on strictly line of sight calculations with an earth radius of  $6.4 \times 10^6$  meters and a satellite elevation of 480 kilometers. (See Figure 2, on the next page.) Refraction due to the atmosphere will undoubtedly extend that percentage somewhat. Lack of stabilization will dictate the use of an omnidirectional antenna(s) which will have a negative effect on the signal-to-noise ratio and on the communications power budget. These problems will be primary concerns of the communications and power supply designers.

#### d. Communications

The radio communications link with the PANSAT is currently planned to have a 437.25 MHz center frequency with a 960 kHz bandwidth. It will utilize the AX.25 amateur packet-radio communications protocol in half-duplex mode at 1200 bps [Ref. 5:p 3]. The reason for the low 1200 bps data rate is two-fold. First, a low data rate will conserve power on the satellite because less bandwidth is required. Second, it will reduce the probability of bit error thereby possibly making forward error correction (FEC) and its attendant hardware and/or software less important and possibly not required.

$$((2 \times 21.53) + 180)/360 \times 100 = 63.29\% \text{ in sunlight}$$

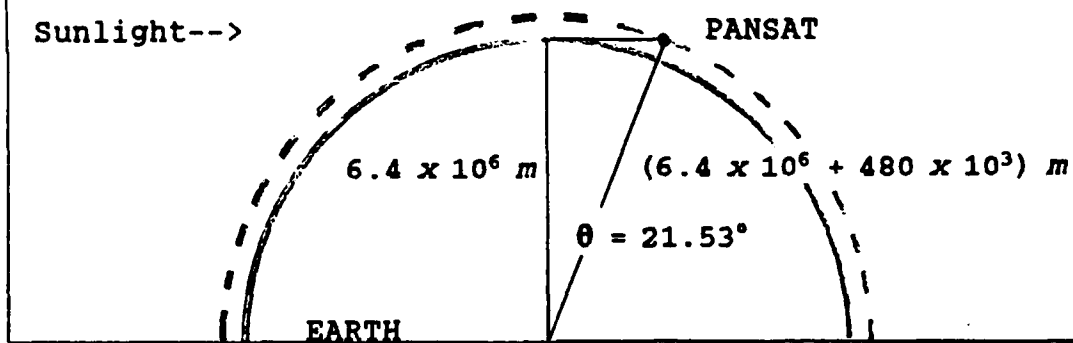


Figure 2. Portion of Orbit in Sunlight

The AX.25 protocol utilizes automatic repeat request (ARQ) at the frame level for error correction. With too high a bit error rate (BER) due to a high data transmission rate this could be too time consuming. But with only a 10 minute or less communications window there is a tradeoff with the desire to keep the data transmission rate

low to reduce the BER and the need to get all the data transmitted during the short window. There is room here for further data transmission rate optimization studies which is primarily dependent on the signal-to-noise (S/N) ratio of the PANSAT/ground antenna/transmitter/receiver system and its chosen modulation method. [Ref. 7:p. 28]

The current communications subsystem design forecasts a bit error rate of  $10^{-5}$  [Ref. 6:p. 19]. This is a probability of one character being incorrect every 2.6 pages. (A page is assumed to be  $60 \times 80 = 4800$  bytes = 38400 bits.) Since there will be a maximum amount of available RAM for telemetry/messages of about 800 kilobytes, it will take about  $800 \text{ kilobytes} / 1200 \text{ sec.} = 90$  minutes to completely load or unload the RAM. But any message of a page or less (about 4800 bytes) will only take about 4 seconds or less to transmit or receive. Most messages will surely be on the order of a page or less.

#### e. Power

The satellite will be powered by an array of 15 volt solar cells mounted on the exterior. These will charge two 10.5 volt lead-acid batteries in parallel. The batteries each consist of five 2.1 volt, 5 ampere-hour cells. The batteries are required, of course, for the eclipsed portions of the orbit. A breadboard version of the power system has been designed and constructed. The nominal power requirements of the PANSAT are not yet known because not all

the systems have been designed and/or built but the breadboarded power system design estimated that 11.0 watts average power will be required, of which the processor's share is 2.6 watts 100% of the time. [Ref. 8]

f. Durability

The satellite will be subjected to high vibration during launch and orbital injection. The overall root mean squared vibration level is 12.9 g's for 40 seconds [Ref. 9:p. 57]. The processor must be able to withstand these stresses without failure.

g. Lifetime

The processor must be able to function properly during the satellite's design lifetime of one and one half years. The design should be such that system failure can be avoided. If a fault occurs, the design should minimize the impact on the mission by redundancy (appropriate to the relative simplicity of the satellite) or by allowing the processor to work around the fault. [Ref. 1:p. 6]

C. PANSAT COMPUTER FUNCTIONS

The following functions are to be performed by the processor:

1. Communications

The satellite will act as an orbital store-and-forward message service. The satellite will be capable of receiving messages via a communications link, storing the

messages, and transmitting them upon request. There should be a way for the processor to transmit a list of its current messages, upon request. Also, messages will have to be periodically erased to free up memory space.

## 2. Telemetry

The processor may store telemetry data from on-board sensors and the satellite will transmit the data upon request.

## 3. Housekeeping

The processor must manage housekeeping functions in support of the mission functions. These housekeeping functions could include, but are not limited to:

- a. Power management and monitoring of power supply voltage, battery charging current, and battery current draw.
- b. Generation and formatting of status messages.
- c. Reception, decoding, and execution of commands from the ground control station.
- d. On-board fault detection and recovery. (Message fault detection and recovery is a function of the AX.25 protocol.)
- e. Ability to update or change programming.

## 4. Transmitter Control

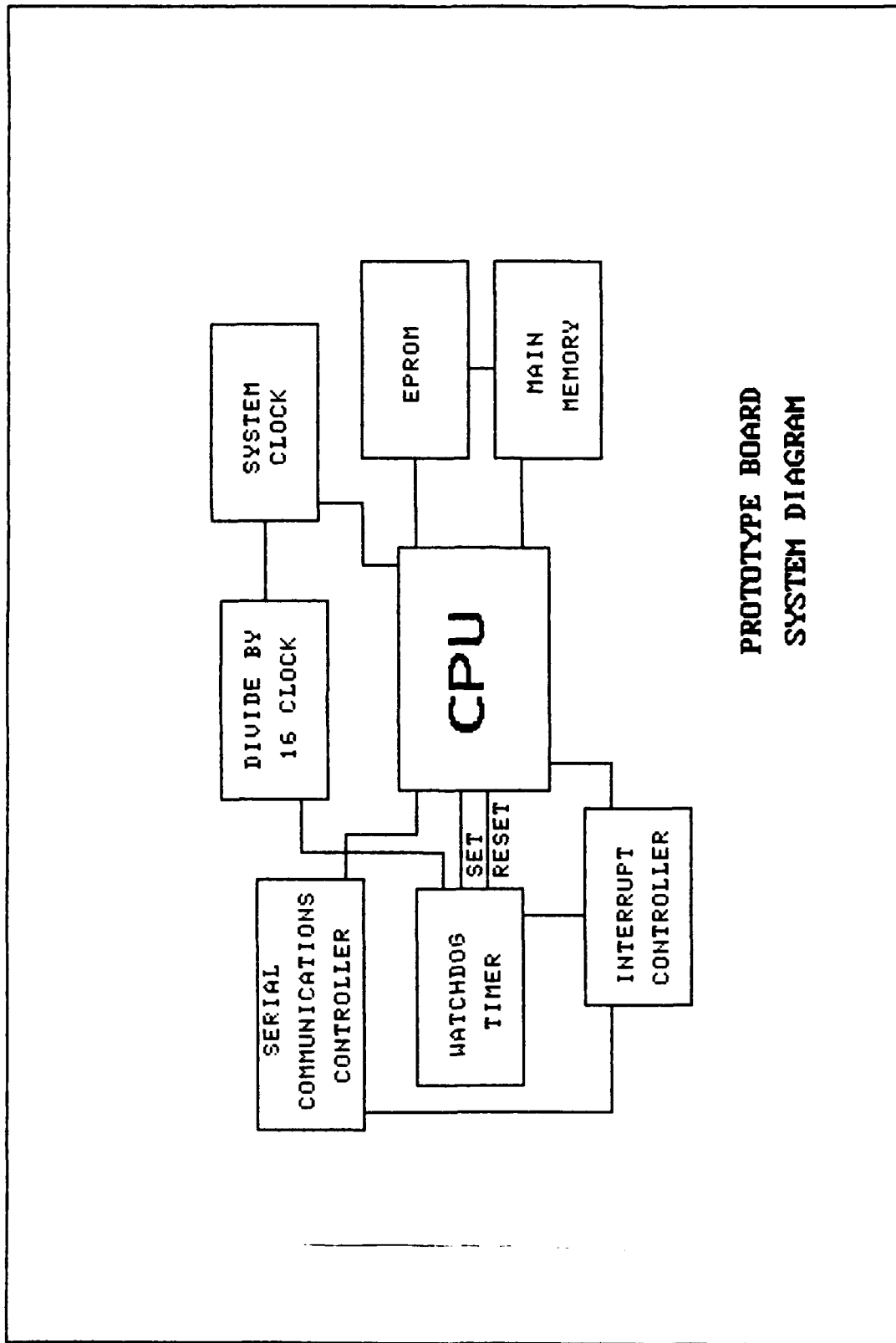
A major concern for getting the PANSAT design approved for launch is demonstrating positive control over the transmitter. If the satellite has a malfunction, there must still exist means to secure the transmitter from the

ground station. Legally, telecommand capability is necessary: "...to turn off a malfunctioning transmitter that might conceivably cause harmful interference to important radio services worldwide." [Ref. 10:p. 12-2]

Transmitter control will be a joint responsibility between the processor and the communications subsystem. During normal operation, the processor will turn the transmitter on and off, but if the processor fails during transmission, the communications subsystem must have a way to secure the transmitter. If the receiver and/or the serial communications controller and/or the processor or software fail with the transmitter keyed on so that the receiver has no way to secure the transmitter, a watchdog countdown timer is provided with the processor to time out and reset the processor, thereby securing the transmitter. Then, if the fault is not correctable, either from the ground or on the satellite, the transmitter is left turned off. Figure 3, on the next page, is the overall computer system diagram. It clearly shows the implementation of a watchdog timer to effect positive transmitter control.

#### **D. DESIGN CONSTRAINTS AND CONSIDERATIONS**

Other microprocessors or microcontrollers available in a low power, radiation hardened version could have been used for the initial design, e.g., the 8085, Z80, MC68000, 8096 (microcontroller), and others, but the 80C86 is a good choice



**Figure 3. Computer System Diagram**

because it is probably better known, with commonly available compilers, assemblers, and software. Most of the following items were considered in the paper design of the processor system in the predecessor's thesis [Ref. 1].

#### 1. Commonality

The processor should be similar to one commonly available. This will simplify program development and allow increased educational benefits. Program development is simplified by the larger number of software packages (i.e., compilers and assemblers) available for a common processor. It is very desirable that the processor have high level language compilers available to allow programming the processor in C or an equivalent language. The educational benefit is enhanced by allowing students to develop a program on a ground-based computer. Once debugged and verified a program can be uploaded and tested on an actual satellite. The 80C86 microprocessor fits this consideration nicely.

#### 2. Upward Compatibility

The PANSAT processor should be one which can be easily expanded to meet the greater demands of ORION. The 80C86 is a less powerful member of the Intel 80x86 family of microprocessors. A more powerful processor, e.g., the 80386, could be substituted for the 8086 with increased speed, memory addressing capability, and multi-processor configuration capability, without the need for much modification of existing software or support tools which will



have been developed and debugged for use in the PANSAT program.

### 3. Reliability

Reliability is one of the most important, if not the most important consideration in the design of a satellite-borne computer system because on-station satellite repair is so expensive. Computer system reliability is a function of design simplicity, operational requirements, the environment and its effect on durability, individual component reliability, and error detection and/or correction capability. Error detection and correction capability is a tradeoff with simplicity of design. The harsh effects of the space environment can be mollified by the use of radiation hardened parts, shielding, thermal control, and (for launch) shock absorbing and vibration dampening mounts. For the design of this simple system one can ensure component reliability by using less than state-of-the-art parts from a reputable company, such parts being well understood and tested with a reliability track record. This again argues for the use of a system based on a common processor like the 80C86 with its attendant memory and commonly used peripheral support chips.

The reference cited below lists some things a designer can incorporate into a spacecraft system to increase its reliability (only that portion of the list applying to the computer subsystem is shown):

- ...
  - Data communications
    - ...
      - Digital error detection and correction techniques
  - Command and Control
    - Hardware testing of parity, illegal instruction, memory addresses
    - Sanity checks
    - Memory checksums
    - Task completion timed
    - Watchdog timers
    - Memory write protection
    - Reassemble and reload memory to map around the memory failures [Ref. 11:p. 342]

Some, or all of these could be used in the final design. The watchdog timer is already incorporated in the design.

#### 4. Estimate of System Reliability [Ref. 12:p. 669-674]

To keep the system simple, there is minimal redundant circuitry. Partial protection from software failure is taken care of by the watchdog timer. The only accommodation to redundancy may be in the inclusion of a duplicate bootstrap EPROM. Will this system, as it stands, be reliable enough? As stated earlier, per diem and travel expenses are prohibitively costly for repairmen to do maintenance on a small, inexpensive low-earth orbit satellite such as PANSAT. However, it is possible and very easy to get a ballpark figure for the overall system reliability to assure oneself that the computer system will be reliable enough. The cited reference explains that reliability, as a function of time,  $R(t)$ , is simply the probability that the system still works

correctly at time  $t$ . The way this function could be derived is to build lots of systems and then plot the number of systems still working against time,  $t$ . Typically, the resulting graph will be an exponentially decreasing curve. See Figure 4.

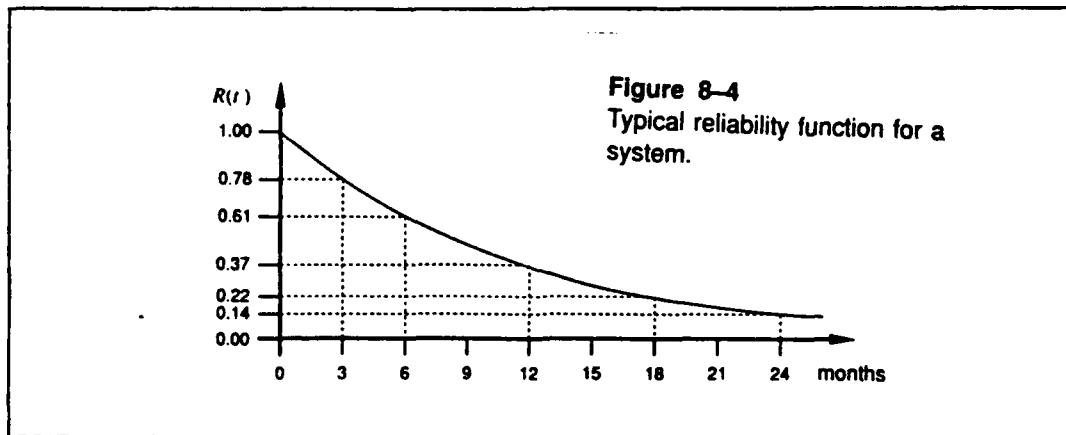


Figure 4. Typical System Reliability Function [Ref. 12]

However, it is impractical and expensive to derive the value for the failure rate by actually building many systems and testing them over a long period of real time. Instead, one takes the reliability information from the specification sheets for the system's individual components. Then one derives the overall system reliability from that information, using a simple mathematical model, to be described below.

Typically, reliability information for electronic components are available from the manufacturer in the form of a failure rate per unit time. This failure rate is usually

expressed by the Greek letter  $\lambda$ . This  $\lambda$  is determined by the manufacturer as follows:

$$\lambda = \frac{\text{number of chip failures}}{\text{number of chips tested} \cdot \text{number of hours tested}} \quad (1)$$

Therefore, the reliability of a component can be expressed as

$$R(t) = e^{-\lambda t} \quad (2)$$

Because the failure rates for electronic components are generally very small, these failure rates are often expressed in a scaled unit called a FIT where

$$1 \text{ FIT} = 1 \text{ failure}/10^9 \text{ hours} \quad (3)$$

These component failure rates are usually not constant, however. They typically display a bathtub shaped curve when plotted against time. See the figure (Figure 5) on the next page.

The high failure rates during the infant mortality portion of the curve are usually eliminated by the manufacturer's burn-in procedure. If a component is going to fail due to improper or borderline manufacture, the defect should reveal itself early on. The manufacturer only ships those components which have survived this initial testing period. Most components never make it to the wear-out stage. The systems containing them typically become obsolete or

Figure 8-5  
The "bathtub curve" for  
electronic-component failure  
rates.

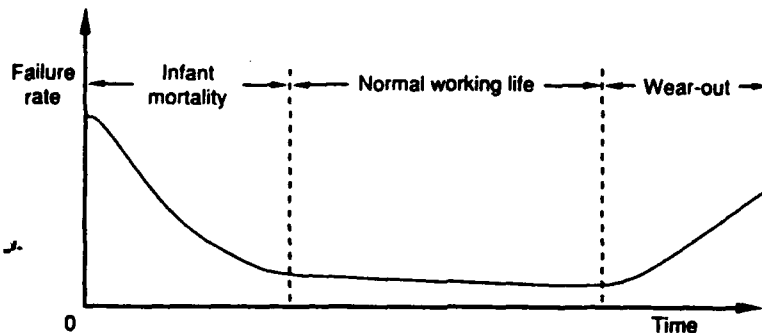


Figure 5. "Bathtub Curve" [Ref. 12]

their physical structure or housing wears out first and the system is discarded. For example, how many people own PCs or VCRs which are more than ten years old? The PANSAT computer system only has to last for up to two years.

There are several factors which can influence the baseline failure rate of components in a real system during its working life. Some of them include temperature, humidity, shock, vibration, radiation, and power cycling. For terrestrial components, temperature is usually the most significant of these factors. The failure rate approximately doubles for every 10°C rise in temperature. This is good news for the PANSAT computer, since it will be operating in

the cold environment of space. However, this advantage must be balanced with the lack of convection cooling to get rid of internally generated heat due to the lack of air.

With known component failure rates from the manufacturer, one can calculate the overall system rate by simply adding the individual component failure rates. This assumes all components are necessary for the system to work, the failure rates are independent of each other, and the failure rate of the component interconnections is minimal.

Specific failure rates are not readily available for specific components. However, failure rates of certain batches or runs of a particular manufacturing process are available for some of the radiation hardened parts [Ref. 13:pp. 14-16--14-20]. For other non-radiation hardened parts, such as the serial communications controller (SCC) or the SRAMs, one can make a rough estimate using Wakerly's text [Ref. 12:p. 674]. The EPROMs, SCC, and SRAMs will be treated as LSI parts. A FIT of 250 will be used for them. For the remaining chips, a FIT of 50 should be conservative enough. Finally, a FIT of 15 will be used for the 50 or so resistors, capacitors, and the crystal. One can calculate the tentative failure rate for the prototype PANSAT computer system,  $\lambda_{sys}$ , as follows:

$$\lambda_{sys} = (9 \times 250) + (15 \times 50) + (50 \times 15) =$$

$$3750 \text{ failures}/10^9 \text{ hours} . \quad (4)$$

The mean time between failures is  $1/\lambda_{sys}$ , or about 30 years.

## 5. Radiation Hardening

Another advantage of using an 80C86 based system, alluded to above, is that almost all the required parts are available in a radiation hardened version. This greatly increases the system reliability (as well as the expense). The low earth orbit that PANSAT will occupy does not strictly require the use of radiation hardened components [Ref. 14:pp. 34,80]. However, reliability vis-à-vis solar and extrasolar radiation (and manmade nuclear EMP) is enhanced by the use of radiation hardened parts. If money is no object they can be used with this design.

## 6. Environment

Consideration of the space environment impacted the design primarily in the selection of components which were available in a radiation hardened version.

### a. Launch

Launching parameters had no direct influence on the design.

### b. Orbit

The orbit has not been determined. But the use of radiation hardened parts will almost certainly gain a reliability advantage regardless of the final orbital

parameters. This again argued for the use of the 80C86 or any other processor available in a radiation hardened version. The orbit also has a direct effect on the frequency and limits of temperature extremes. Because PANSAT is small and inexpensive, the only thermal stabilization will come from the satellite structure design and subsystems placement, and possibly reflective or absorptive coatings. The processor and support chips are available which will operate reliably in the range of approximately  $-55^{\circ}\text{C}$  to  $+125^{\circ}\text{C}$ .

#### 7. Power

Available power on a satellite is limited. Static power consumption was a consideration in choosing the 8086, because it is available in a CMOS version, the 80C86. CMOS consumes much less quiescent power, although dynamic power consumption is a linear function of operating frequency.

#### 8. Communications Protocol

The tentative communications protocol to be used is the AX.25 amateur packet-radio link-layer protocol. This protocol follows, in principle, the CCITT X.25 protocol, with the exception of an extended address field and the addition of an Unnumbered Information (UI) frame. It was designed to be a mechanism for the reliable transport of data between two signaling terminals, in this case between a satellite and a ground station. [Ref. 15:p. 1]

##### a. Error Detection

Both the sender and receiver calculate a frame-



check sequence to make sure a frame was not corrupted by the medium. In addition, there are several link-layer errors which are recoverable without terminating the connection due to things like the I frame information field being too long, or the reception of a frame with an invalid Send Sequence Number (N(S)).

**b. Error Correction**

The protocol handles communications errors by retransmission. Errors due to transients in the medium or the hardware can be fixed this way. A permanent hardware fault in a ground station, once detected by the protocol, can be fixed. There are limited options for error correction if a hardware fault occurs on the satellite. Hardware redundancy with automatic switching upon error detection, or switching commanded from the ground are options, but to keep the design simple hardware redundancy and error correction have been forgone. The emphasis has been placed on hardware reliability, negating the requirement for (hardware) error correction.

**E. PREVIOUS FLIGHT DESIGNS**

At least three other satellites have been launched with successful missions similar enough to that of PANSAT to provide useful information and insights. Taken together, they show that amateur packet radio store-and-forward message

service with the AX.25 communications protocol is feasible. It can be done because it has been done before.

#### 1. UoSAT-2

The UoSAT-2 was designed to investigate the technical feasibility of store-and-forward communications via inexpensive satellites. It was launched in 1985 into an 800 kilometer polar orbit and it was designed to operate for more than three years. It utilized a NSC-800 processor running at 0.9 MHz. The communications link operated at 1200 bps, using a custom message protocol (MSG2). The kernel implementing the protocol was written in Z-80 assembler code and occupied 2.5 kilobytes of error detection and correction protected (EDAC) 12 bit wide RAM. This satellite was the first civilian demonstration of an operational store-and-forward communication system. Its on-board EDAC hardware provided invaluable data on the frequency of hard and soft radiation induced errors. It found that about 6 single-event upsets (SEUs) per day would occur in a 1 megabyte commercial grade CMOS memory in that orbit. Of course, the SEU rate depends on: [Ref. 16]

- Memory device manufacturing technique (radiation hardening)
- Device geometry
- Shielding
- Satellite orbit
- Satellite attitude
- Solar activity
- Geomagnetic activity

## 2. UoSAT-D

The UoSAT-D was a packet communications experiment that built on UoSAT-2. It implemented the AX.25 packet radio protocol operating at 9600 bps in full duplex mode. It utilized an 80C186 processor running at 8 MHz. Its mission was to support amateur packet-radio communications using low earth orbit satellites and to study the orbital radiation environment and its effects on semiconductors. [Ref. 17]

## 3. FO-12

The FO-12 was the first Japanese amateur satellite, launched in August of 1986, to serve as a store-and-forward digital mailbox. It implemented the AX.25 protocol with four uplink channels and one downlink channel, all operating at 1200 bps. No ROM was used. Only DRAM was used. Initial program load was accomplished via hard-wired logic. The FO-12 also used a NSC800 processor. [Ref. 18]

## **II. ORIGINAL DESIGN CHOICES/PROTOTYPE CHANGES**

Changes have been made to the original design primarily for three reasons--expense, advance in the state of the art, and expediency. For the prototype, military standard or commercial grade were substituted because they are functionally equivalent and much less expensive. The wire-wrapped breadboard and flight model components may also have to be changed in response to changing mission requirements.

### **A. PROCESSOR SELECTED**

The prototype uses an 80C86 microprocessor, commercial grade, instead of the 80C86RH radiation hardened version because they are functionally equivalent and the 80C86 is much less expensive. This expense was the main reason for chip substitution for all the other chips, with the exception of the Zilog serial communications controller (SCC). See below.

### **B. PROCESSOR MODE**

The prototype stayed with minimum mode instead of maximum mode because this is still a small stand alone system.

### **C. BUS DEMULTIPLEXING**

The wire-wrapped prototype still used the 54HC573 octal D-type address latches and the 54HC245 octal tri-state data

bus transceivers because there was no need to change them. They are available in radiation hardened versions and are fast enough to operate at 5 MHz.

#### D. CLOCK AND PERIPHERALS

##### 1. Analog to Digital Converter

The A/D converter is not implemented, but it would be straightforward to implement once the telemetry/sensor requirements are determined.

##### 2. Parallel Port

For the same reason, the parallel port is not implemented.

##### 3. HDLC

The CMOS 85C30 was substituted for the "TTL only" 8273 HDLC because the anticipated orbit was changed to a lower one and radiation hardening was determined to be not as critical. The 8273 was not available in a CMOS version at the time of the original design. The TTL 8273's radiation immunity was traded for the reduction in power consumption by using the CMOS 85C30 serial communications controller.

##### 4. Timer

The 82C54 programmable interval timer is still used. Its primary function is to serve as the transmitter control watchdog timer. For some of the testing, a functionally equivalent subset, the 82C53, was substituted.

## 5. Interrupt Controller

The 82C59 programmable interrupt controller is still used.

## 6. I/O Device Chip Selection

The 54HC138 3-line to 8-line decoder/multiplexer is still used. However, the address selectors were changed to A7 through A10, instead of A3 through A5, for added flexibility [Ref. 19].

## 7. Clock

The 82C85 static clock controller/generator and the 74C161 synchronous binary counter are still used.

## 8. I/O Device Timing

There has been no significant change.

## 9. Reset

The 82C54 still acts as the watchdog countdown timer. If the processor is operating properly, the watchdog timer will be reset before it has a chance to time out and reset the processor. However, in the original design, if the timer timed out, a flip-flop would switch to an identical ROM and the system would reinitialize. This would provide for the correction of a hard fault in the first ROM. In the interest of expediency, the actual flip-flop and extra ROM was not built. It would be easy enough to include it in the flight model, however.

## 10. Miscellaneous changes

A reset switch has been added to the prototype for an

on-board reset capability and an LM7805C 5 volt voltage regulator chip have been added to the board between the external power and the rest of the board. Also, an MC1488 line driver chip and an MC1489A line receiver chip have been added to the board for conversion of the RS-232C voltages of +4 volts and -3 volts to the CMOS logic voltages of 0 and +5 volts, respectively. The RS-232C connection should be used to download program code or test messages during the next phase of the board's testing.

## **E. MEMORY SYSTEM**

### **1. (E)PROM**

The original design used two 2k x 8 bit PROMs in tandem. The breadboard prototype uses two 128k x 8 bit TMS27C010 PROMs in tandem. This is certainly more than is required for the on-board operating system, or at least the boot-strap kernel, but it made the construction symmetrical and gives plenty of room for experimentation.

### **2. Vital RAM**

The wire-wrapped prototype doesn't have a vital memory section. The actual size of protected memory required can not be determined without a firmer idea of how much telemetry or other vital data will be required. One could go back to using the current 128k x 8 PROM memory space and splitting it into a much smaller actual PROM portion with the balance of the 128 k x 8 space being taken up with radiation

hardened/shielded redundant SRAM. Perhaps this address space could be occupied by special 12 bit EDAC memory as in the UoSAT-2.

### 3. Bulk RAM

The original design used 32k x 8 bit SRAM chips with extra 54HC138 multiplexers and 54HC32 OR gates for addressing. Due to rapid advances in the state-of-the-art, 128k x 8 bit memory chips were available for the wire-wrapped prototype, dividing the RAM memory chip count by four and eliminating the need for five 138 decoders and eight 32 hex OR gate chips.

## F. LOGIC DEVICE FAMILY SELECTION

### 1. CMOS v. TTL

The original design was done with CMOS instead of TTL because, as can be seen in Figure 6 on the next page [Ref. 20:p. 569], all the CMOS logic families use less power than their TTL counterparts and most CMOS families are fast enough to operate at 5 MHz (With the exception of the C family.)

In addition to reliability, low power consumption is a primary goal in the design of satellite circuits. The following three differences dictated the use of CMOS versus TTL components in the design. Factors which determined the particular family of CMOS selected are also discussed.

#### a. Speed

As stated, for the breadboard prototype, CMOS was



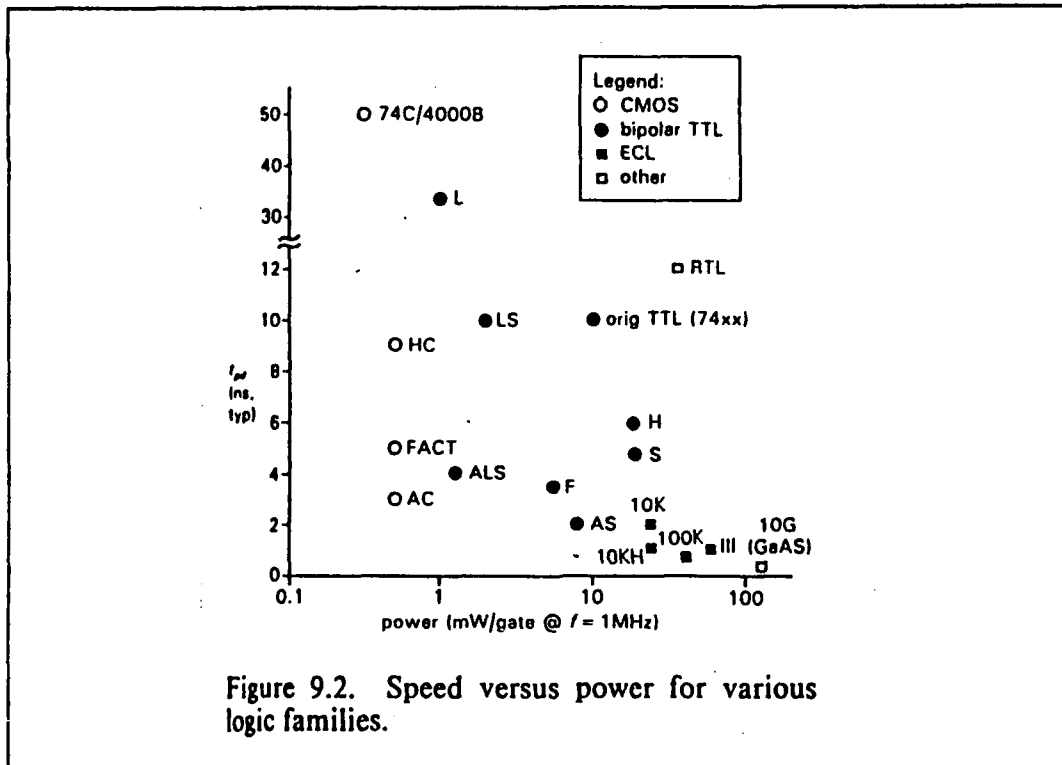


Figure 6. CMOS v. TTL Relative Power Consumption & Speed [Ref. 20]

used because at 5 MHz CMOS dissipates less power than TTL although many TTL families are as fast or faster. But this is not a high speed design. The CMOS HC family was specifically selected for the design, instead of the C family because "...The speed range of CMOS goes from about 2 MHz (4000B/74C at 5V) to about 100MHz (for AC/ACT)." [Ref. 20:p. 486] Because the processor is only being driven at 5 MHz, or less, speed considerations argue for the use of CMOS HC family parts or faster. The 82CXX family of parts, used because of the ease of conversion to a nearly totally radiation hardened circuit, all operate to at least 5 MHz or better.

### b. Power

One disadvantage of CMOS is that, as the operating frequency increases, so does the power dissipation. Even so, the total power dissipated at 5 MHz will still be well below that of TTL. [Ref. 20:p. 487] Figure 7 shows this clearly.

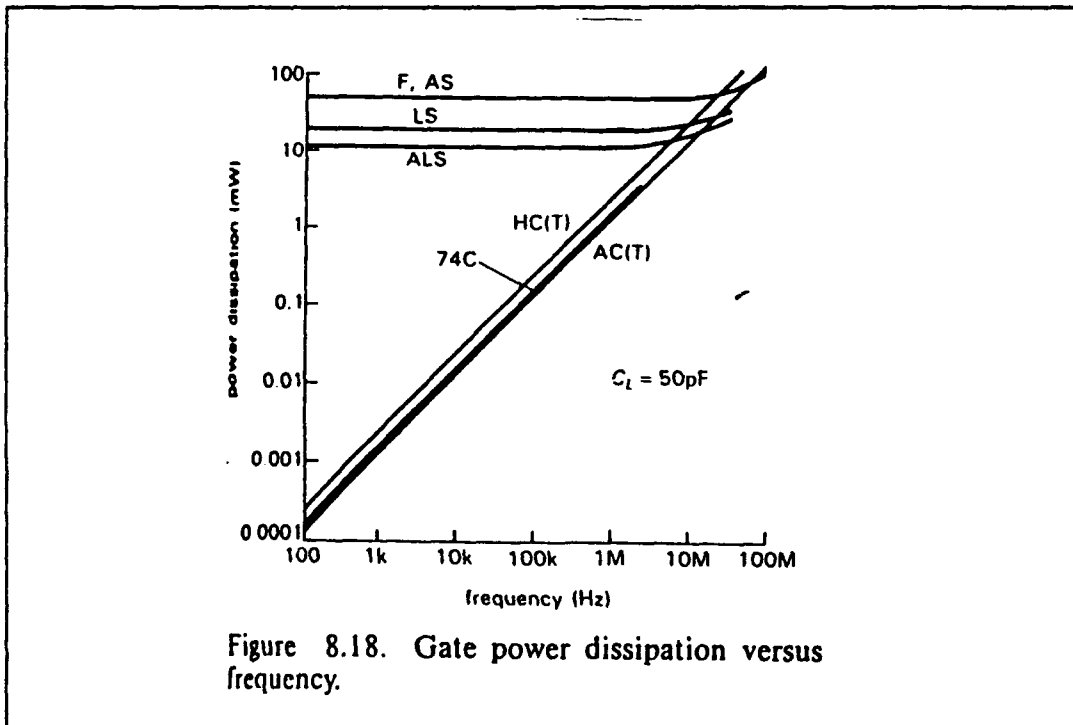


Figure 8.18. Gate power dissipation versus frequency.

Figure 7. CMOS Power Dissipation v. Frequency [Ref. 20]

### c. Noise immunity

CMOS has slightly better noise immunity than TTL, for most circuit configurations. HC and AC family CMOS have the best noise immunity of all the CMOS families. [Ref. 20:p. 569]

## 2. Compatibility

Any CMOS family, operating at 5 volts, is compatible with any other CMOS family [Ref. 20:p. 569]. It is probably best to have all the parts of a circuit be of the same family, which is the HC family in this case.

## 3. MIL-SPECS

Finally, for the parts other than 82CXX, the 54HCXX versions should be used for the final flight version of the circuit. The 54 prefix means that the component meets more rigorous temperature and reliability standards than the commercial grade series, 74. For example, a 54 series component will be able to operate in a temperature range of  $-55^{\circ}\text{C}$  to  $+125^{\circ}\text{C}$ , and can withstand + or - 10% power supply variations whereas a 74 series component can only operate from  $0^{\circ}\text{C}$  to  $70^{\circ}\text{C}$  and can only withstand + or - 5% power supply variations [Ref. 21:pp. 244,247]. That extra temperature margin, especially, could be important in the harsh environment of space. (Some schematic components are designated as 74 series.)

### III. WIRE-WRAP CONSTRUCTION AND TESTING

#### A. BOARD LAYOUT

The layout of the board with its components is shown in Figure 8 on the next page. One can see that the chips are as close together as possible, consistent with having enough room to install filter caps and/or current limiting or pull up resistors if or when needed. An attempt was also made to arrange the components so as to minimize wire lengths while taking into account the required circuit interconnections.

##### 1. Wire Size(s)

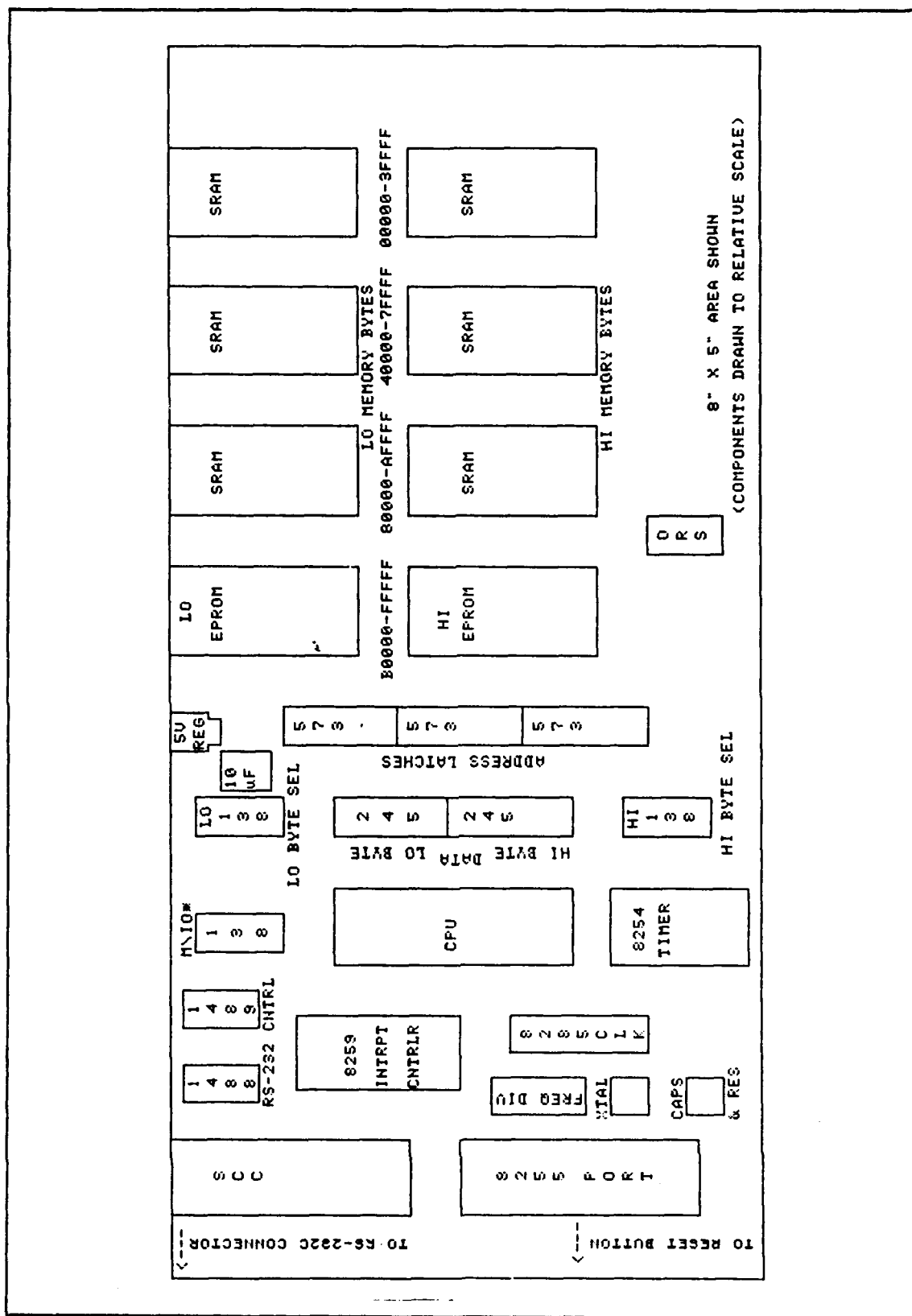
The wire size used was AWG 30. One of the references, however [Ref. 21:p. 119], recommended that AWG 20 be used for all IC power and ground lines. Unfortunately, the wire wrap tool is designed for AWG 30. One solution would be to make double runs of the AWG 30 wire to simulate AWG 20. However, all the chips drew so little current that voltage drop was not a problem. The wall power supply current meter never read more than about 80 milliamps.

##### 2. Heat Dissipation

With CMOS, heat dissipation is not really much of a concern. On the prototype board the chips have stayed cool to the touch, even during extended periods of testing.

##### 3. Component Placement to Minimize Wire Length

The components were not just arbitrarily placed on



the wire-wrapped board. The components were placed so as to minimize wire lengths. Some of the reasons for minimizing wire lengths are described below.

a. Stray capacitance

Stray capacitance's effect on a digital circuit is to act as an AC load. An AC load is undesirable because it can slow down transition times. There are at least three things which can cause stray capacitance in a digital circuit:

- Output circuits--typically several pF
  - Input circuits--typically from 2 to 15 pF
  - The wiring that connects outputs to other inputs--typically 1 pF per inch, or more.
- [Ref. 12:p. 74]

The first and second items are inherent to the I.C. packages themselves. The only factor which the wire-wrap circuit builder has control over is the length of the wiring. Fortunately, the circuit is only being driven at 5 MHz, but even so, a conscious effort was made to minimize wire length. Rise-times on any of the tested signals were not observed to be a problem. There were, however, significant voltage spikes on many rising and falling signal edges.

b. Signal Degradation and Power Drop

Standard wire-wrap size wire, 30 AWG, was used. This seemed to be at odds with the reference [Ref. 21:p. 119] which recommended at least 20 AWG or larger for all logic IC power and return lines. (Although this reference is

presumably more concerned with higher speed circuits.) Wires with a smaller cross-section are more prone to noise pickup and power drop per unit length. However, because CMOS was used with a low current draw and the computer could fit all on one board in a 5" by 8" area, the 30 AWG wire seemed to work. Double wire runs were started on some of the power and ground lines, to increase the effective AWG, but the effort was abandoned when initial testing seemed to indicate that noise and voltage drop were not a problem.

#### c. Propagation Delay

Another reason one should try to keep the wires as short as possible is to minimize the effects of propagation delay. Too much propagation delay could have a deleterious effect on the circuit. Such things as clock skew or missed "gates" or "windows" could cause circuit malfunction if one or more lines are particularly long compared to others. [Ref. 22:p. 119]

#### 4. Filter Capacitors

In accordance with the *Logic Designer's Manual* [Ref. 22:pp. 117-118], a 10 microfarad capacitor was placed in parallel with a 0.01 microfarad capacitor across the incoming 5 volts from the wall power supply. A filter capacitor is used to help reduce noise. This is recommended whenever power supply lines run an "appreciable" distance to a board. However, an LM7805 5 Volt voltage regulator was later added to the board negating the requirement. Strictly speaking,

these capacitors are only recommended for circuits operating above 10 MHz anyway. However, with the fast switching times of the HC chips, harmonics may be generated which may be partially shunted by these two capacitors. It shouldn't hurt to leave them on the board. Additionally, a 0.1 microfarad bypass capacitor was placed across the power and ground connection of each chip. The reference recommends a value of 1 to 10 microfarads, but the experienced Space Systems electronics technician [Ref. 23] recommended the 0.1 microfarad capacitors be used instead.

## **B. CMOS POTENTIAL PROBLEMS/CONSIDERATIONS**

### **1. Unused Inputs**

One slight disadvantage of CMOS versus TTL is the requirement to tie all unused CMOS inputs high or low, as appropriate, even for unused gate sections in the same package. With TTL, one can ignore unused sections of a single chip, as well as unused input lines within a particular circuit on a chip. This is not true with CMOS. If one leaves any input line unconnected, the input level could float up to the logic threshold. This could result in both MOS output transistors conducting, resulting in excessive current draw. [Ref. 20:p. 580]

Refer to Figure 9 [Ref. 20:p. 485] on the next page, which is a standard CMOS AND gate. Suppose, for example, inputs A and B were unused but not tied off. One can see



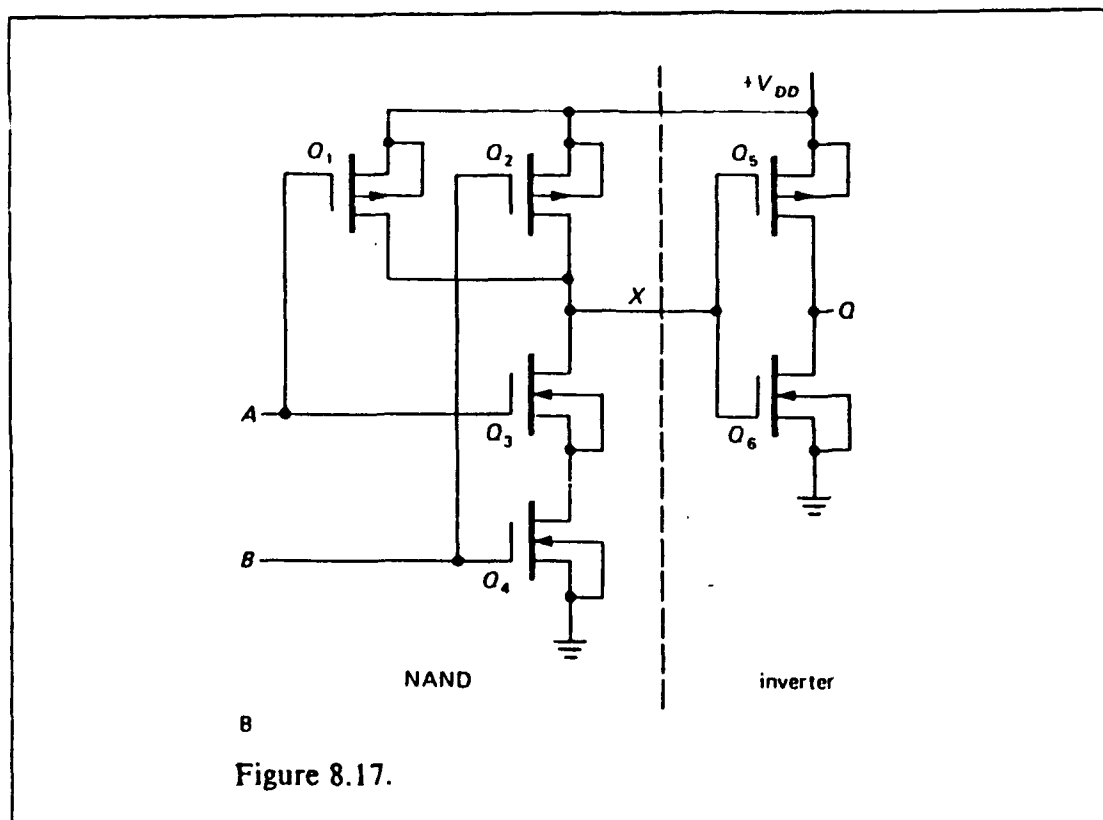


Figure 9. CMOS AND Gate [Ref. 20]

that if both of these inputs floated high enough to bias Q3 and Q4 on, but not high enough to bias Q1 and Q2 off, the resulting current flow through the low resistance path from +V<sub>DD</sub> to ground could be excessive. This could cause latch-up (described below) resulting in temporary or permanent damage to the part.

## 2. Latch-up

"All CMOS devices are intrinsically susceptible to latch-up, which occurs when internal parasitic silicon-controlled rectifiers (SCRs), structures that are inherent in CMOS integrated circuits, are triggered on." [Ref. 21:p.57]

The three small figures directly below (Figure 10) help to

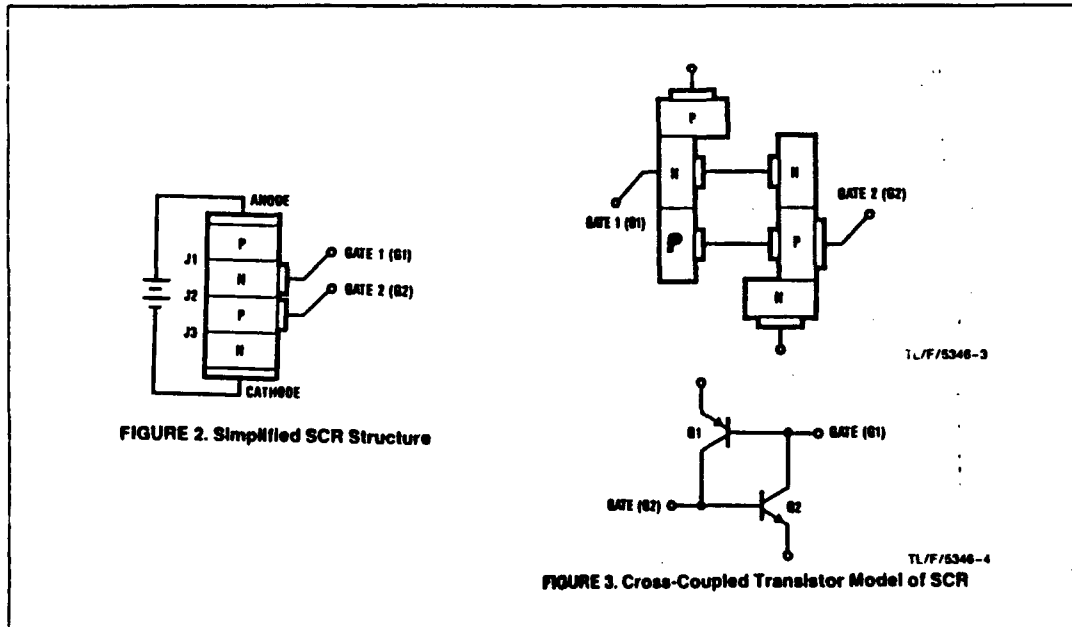


Figure 10. CMOS Latch-up Process [Ref. 24]

explain the inherent problem of CMOS latch-up.

The small figures show the simplified SCR structure inherent in all CMOS devices, the effective cross-coupled transistor operation of the junctions during latch-up, and a simple circuit model of the two "transistors" involved. Normally, gate 1 and gate 2 will be at the same potential. But suppose a large positive voltage is placed across the anode and the cathode of the SCR structure on Q1. The process of latch-up can be described as follows: If enough leakage current can flow from Q1's anode to its cathode, thereby biasing Q2 on, then more current will be on gate 1, biasing Q1 on even more. This is a runaway situation which rapidly leads to saturation. [Ref. 24:pp. 2-112--2-113]

However, latch-up should not be a problem anymore with the current production methods used to manufacture the

54HCxxxx parts [Ref. 24:p. 2-112]. The latch-up problem has been eliminated with the Harris radiation hardened parts as well [Ref. 25:p. 2-11]. These are the most likely components to be used in the final design.

### 3. Pull up Resistors

Pull ups (or pull downs) are only required if one is driving a CMOS input with a device that has an open state [Ref. 20:p. 579]. Pull downs can be used for CMOS but they are not effective for TTL. For CMOS, noise immunity is the same with either pull ups or pull downs and there is no current draw through the resistor for either choice when the driving device is open.

There is no need for pull ups in this design. The only three state devices used in this design are the 573 octal latches and the 245 octal transceivers. The 573s are permanently enabled and any device driven by the 245s has a *chip select* signal. For example, in between *data enable* assertions, the outputs of the 245s are in a high impedance state. This is not a problem because none of the devices driven by this input, e.g., the interrupt controller or the SRAMs, will be chip selected at this time. Therefore, one will not load the devices with unpredictable data and no pull ups are required.

### 4. Fan out

Because all the components are CMOS (with the exception of the RS-232 drivers, to be used for testing,

which are NMOS), fan out should not be a problem with the design, with the possible exception of the read signal. The read signal is the worst case. Any of the outputs should be able to easily drive at least 10 other inputs [Ref. 20:p. 487]. The read signal goes to the eight memory chips, the timer, the interrupt controller, and the SCC, for a total fan out of 11. This should still be acceptable.

#### 5. Fast Rise-times and Harmonics

These are a concern with the newer CMOS logic families [Ref. 21:p. 5] such as HC used in this design. The fast rise-times have two major deleterious effects: Faster rise-times generate higher harmonic frequencies, and faster rise-times result in greater transient voltage swings.

The bandwidth of the interconnection network on a wire-wrap board will limit the amplitude of the higher frequency components and the inductance will result in transient voltage spikes. This was observed on the signal traces in the lab and already mentioned above. The data bus signals, especially, which are interconnected with many more wires than most other signals, clearly showed variations in voltage levels. Also, voltage spikes of about 0.75 volts (or more) were observed on the system clock, for example. These problems were minimized by paying attention to the component layout, where the shorter all the interconnecting wires were, the better, as recommended in the reference [Ref. 21:p. 84].

## C. INCREMENTAL TESTING

### 1. Clock and Clock Frequency Divider

First all unused inputs to the 82C85 and the 54HC161 were checked to make sure that they were tied either high or low. Then they were plugged into their respective chip holders and power was applied to the board. The 82C85 was putting out a 5MHz, zero to five volts clock on pin 2. The 161 was putting out a 0.3125 MHz clock (5MHz divided by 16) on pin 11. The clocks had noise of approximately 0.75 volts peak-to-peak centered around either the zero or five volt reference level. See Figure 11 on the next page.

### 2. CPU, EPROM, Latches, and Data Transceivers

After verifying that the 82C85 was putting out an acceptable clock, the next step was to verify that the CPU and EPROM, with their integral latches and data transceivers, were at least nominally functioning. This was done by hand coding the simplest program possible (five bytes) and burning it into the EPROMs. (Appendix A has the 8086 machine language code and the program code is in Appendix B.) The EPROMs come from the manufacturer initially "programmed" with 128K bytes of "1"s, or "FF"s. (Programming or burning the EPROM changes appropriate bits to "0"s.) The program is simply one statement--an unconditional jump to itself.

A 100 MHz oscilloscope was used to verify that the EPROM *chip select* signal (*CS\**) was being asserted at the same time as the CPU *read* signal (*RD\**) on pins 22 and 24,

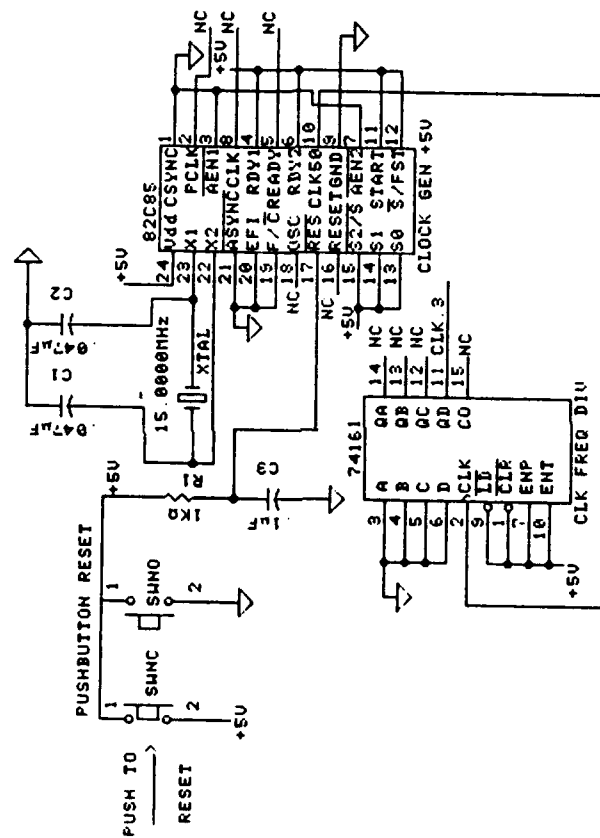


Figure 11. Clock Circuit Schematic

respectively, of the EPROM. Also, the address and data lines on the 573 address latches and the 245 data transceivers were checked to verify that all but A3 through A1 stayed high and that the 16 data bits changed appropriately to reflect the data transfer of "00EA", "FF00", and "(FF)FF". The relevant parts of the board for this CPU loop test are shown on the next two pages in Figures 12 and 13.

### 3. Memory

Next, to do an initial verification test of SRAM, a 25 byte hand coded machine language program was burned into the EPROMs for testing. (See Appendix C.) The program would jump to the start of a routine. The routine would set up the data segment register for a segment located in memory. Then a memory location (byte) would be loaded with the arbitrary number "05". Then there is a NOP (no operation) in the code. Then the same memory location is read and the value there (should be "05") is loaded into the DL register. Finally, the routine jumps to the initial jump command and the program repeats.

As above, an oscilloscope was used to verify that the address and data lines were what was expected, as well as verifying that the 2 *chip select* signal assertions and the *read* and *write* signal assertions happened at the right times with respect to each other. They did.

Figure 14 follows Figures 12 and 13. It shows the complete memory schematic used for this and subsequent tests.

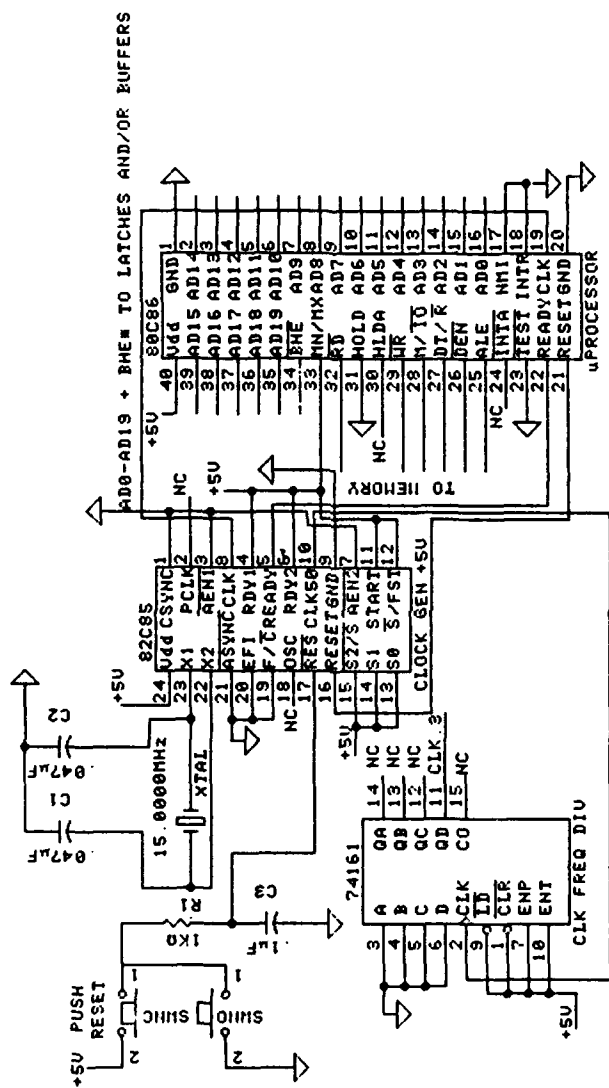


Figure 12. Loop Test Schematic--Clock and CPU



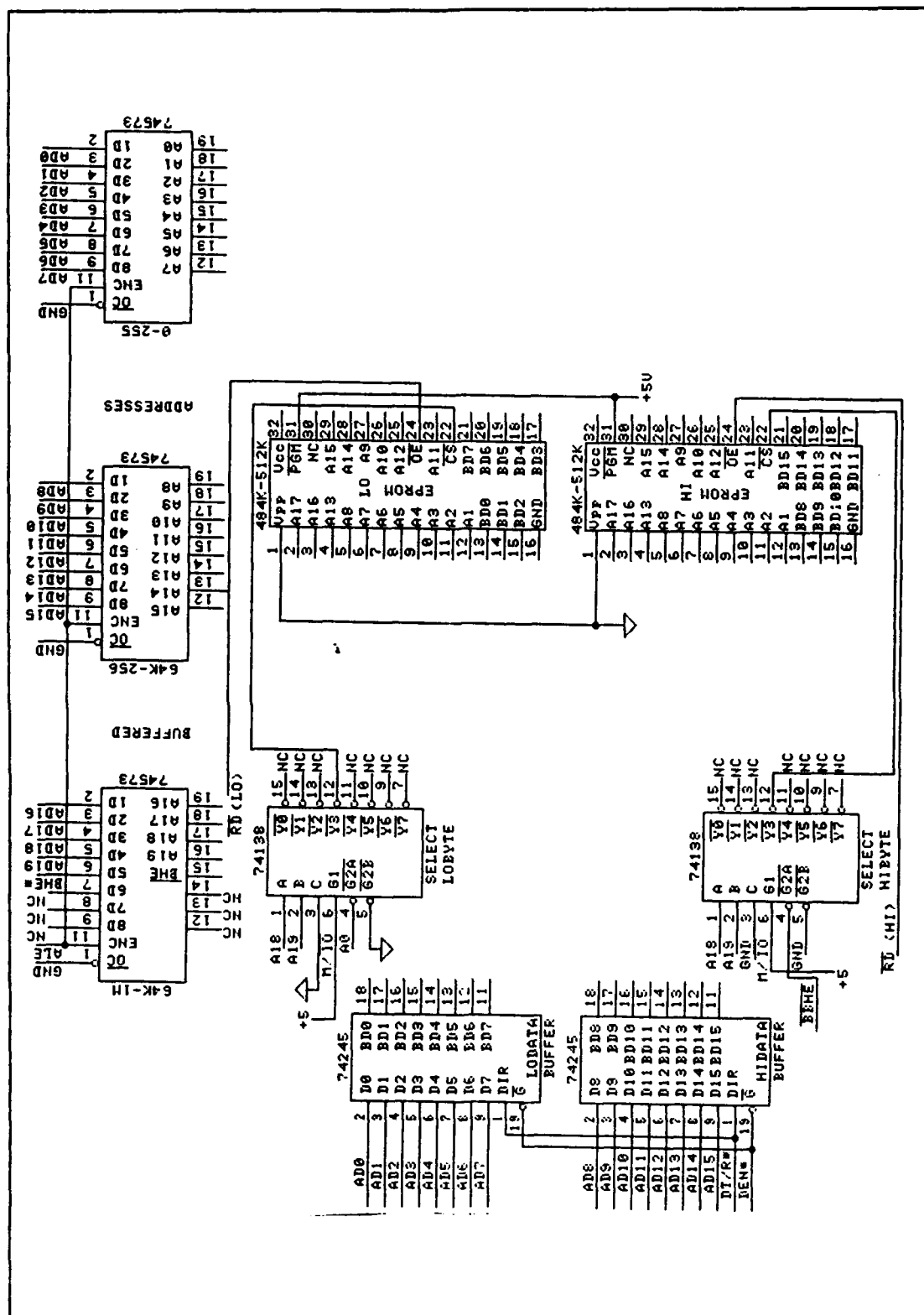


Figure 13. Loop Test Schematic--EPROM Only

**Figure 14. Complete Circuit Schematic--Memory**

#### 4. The Need for a Monitor

But now there were 15 reads and 1 write per program "cycle." It was becoming difficult to unambiguously verify correct circuit operation. It was becoming evident that a better way to monitor circuit operation than sticking an oscilloscope probe on various chip pins would need to be found. Also, the capacitance of the oscilloscope probe, itself, has the potential to change the circuit parameters (for HC CMOS, at least) just enough to make a circuit work which otherwise would not, or vice versa [Ref. 20:p. 575].

In fact, this phenomenon was observed in the lab. Often, the oscilloscope would indicate the circuit was not operating properly and would have to be reset, as one went about the circuit with the probe checking inputs or outputs on various pins. However, if the probe(s) was (were) clamped onto the circuit and a correct oscilloscope trace was obtained, the trace would remain unchanged for two hours or more. This was observed several times.

This also argues for a more reliable and less invasive means of monitoring the circuit performance. So the next goal, after completion of the complete incremental system check out, should be to set the board up with an RS-232C connector. Then the board could be hooked to a CRT monitor. The Space Systems technician had a monitor program available, written in assembly, which would allow the target board to be hooked up to a PC host. If this monitor program

and hardware were installed, then one could write assembly, or higher level compiled programs, which could then be downloaded to the target RAM. This would eliminate the requirement for the tedious bother of machine language level hand coding and burning of the EPROMS.

But the monitor program requires extensive modification for application to the board's particular components and configuration. This has been left for the student(s) who will follow on. There was not enough time to sidetrack into the extensive set up of the complete monitoring system.

#### 5. Timer

Before testing the timer directly a short program was written to test the M/IO\* selection circuitry. This was done by running a program which would run a continuous loop which would select the unused pin number 10 (Y5 on the schematic) on the 54HC138 decoder with an appropriate OUT statement. (Register DX already having been loaded and register AL being all *don't cares* in this case.) (See Appendix D.) A periodic high pulse was observed when the IO command OUT was executed and pin number 10 on the 138 IO decoder was periodically selected. Figure 15 on the next page shows the pertinent circuitry.

Now that the M/IO\* selection circuitry was shown to be working, the next step was to write a simple test program for direct testing of the 82C54 programmable interface timer.



Counter 2, Mode 3, was selected with an initial count of four. This should have resulted in a square wave on the *OUT2* output with a period of four 82C54 clocks. That is what was observed. (See Appendix E.)

#### 6. Interrupt controller

Originally, this was to be the final portion of the piecemeal testing of the hardware components. It was also the most difficult. Initially, a program was written to test both the 8259 and the SCC at the same time. The timer was used in Mode 0 to provide a periodic interrupt signal. (In Mode 0, the timer stays low until it times out; then it goes high.) Part of the interrupt service routine (ISR) was to reset the timer as well as read a previously stored character from memory and write it to the SCC which would put the character out at 9600 baud.

But this turned out to be too ambitious for one program (i.e., it would not work), so the program was split into parts. Thus, the SCC was left out of its holder and the program would just put out the stored character to the SCC port address. It was hoped that the data's periodic presence on the SCC chip holder data pins would be observable. This would verify proper operation of everything except the SCC itself.

The SCC could be tested separately, without using the timer or the interrupt controller, by having the CPU poll the SCC until its transmit buffer was empty and it would then be

ready to accept another character from the CPU. Then, after all the components were verified as functioning correctly, they could all be tested as a complete system much more effectively after implementing the suggested monitor program with the RS-232C protocol.

This test of just the timer and the interrupt controller could not be made to work, either. It appeared as though the timer was not being reset, because *OUT2* stayed high and the CPU was cycling through low memory. Evidently, the CPU was putting the return address on the stack and then it was being immediately interrupted again, whereupon it again put the return address on the stack, and so on. The act of cycling through low memory indicated that the stack segment and the stack pointer had not been initialized.

But even so, the program still should have worked. The return address would just be located at 00000, 0FFFF, 0FFFE, and 0FFFD.

So the interrupt controller testing program was again broken into smaller parts with the first part being a test of the timer, alone, in Mode 0. (See Appendix F.) This first incremental program was finally made to work, but only after discovering that the 8254 data sheet's functional description was wrong.

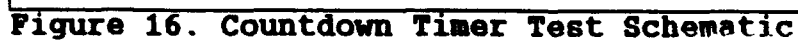
But first, it was thought that it might be a problem with the timer taking too long to go low after being reset. Since the 8259 is clocked 8 times faster than the timer and

the CPU is clocked 16 times faster than the timer, perhaps the 8259 reset was happening too quickly upon the heels of the timer reset? This is why there are delay loops between the timer reset and the 8259 reset. After the real problem was discovered, it was realized the delay loops are almost certainly not necessary, but it doesn't hurt to have them there to remove all doubt.

The first increment of the 8259 testing program shows what was later realized to be probably the main or only reason why the original program did not work. The data sheet on the 8254 timer is wrong. The data sheet says that once the timer times out in Mode 0, one needs only to reload the control word (CW) or reload the count and the timer will resume counting. Evidently, one needs to reload both the CW and the initial count for the counter to resume counting. The timer stayed high if one reloaded the CW, only. When one ran the program which resets both the CW and the initial count, suddenly the address and data lines and the timing relationships were all as expected. Figure 16 on the next page shows the circuit for the testing of the 82C54 (or 82C53) countdown timer.

The second increment of the interrupt controller testing used the timer in Mode 0 to provide the periodic interrupt. (See Appendix G.) *OUT2* is used as a signal to the 8259 on *IR3* that there is an interrupt to be serviced. The 8259 alerts the CPU with the *INT* line. The CPU replies with





*INTA\** and the 8259 gives the CPU the address of where to look for the address of the interrupt service routine (ISR). (The ISR address and the ISR itself must have first been loaded into memory.) The ISR just resets the timer. One must be careful not to enable interrupts until the timer actually goes low again. Otherwise, the CPU will keep interrupting itself and the ISR to reset the timer will never be executed and *OUT2* will stay high (causing interrupt upon interrupt) and the CPU will cycle through memory doing nothing but continually putting the return address on the stack, as already discussed above. (See Figure 17, next page.)

Also for the reasons already discussed above, it was very difficult to verify proper circuit operation for this increment. The only way to verify the circuit now was to trigger a trace on the oscilloscope with something like one of the ISR SRAM chip selects and check to see if the cycle time was what would be expected if the program were operating properly. Sometimes the reset button had to be pressed several times to get a steady trace with the correct cycle time. It was not clear, though, if the instability was an artifact of improper circuit operation or of a problem with the scope triggering mechanism.

Finally a steady trace was obtained from the *chip select* signal on the stack segment low byte SRAM (memory locations 40000 to 7FFFF). On the 0.02 msec per division scale, the cycle was 8.5 divisions long. This is 0.00017



seconds per cycle. Since the counter is loaded with 2Fh (= 47d), it should take  $47d \times 1/(5 \text{ MHz}/16) = 0.0001504$  seconds to complete. But of course, there is overhead time in reinitializing the counter when it times out. The return address has to be placed on the stack and the vector address of the ISR has to be loaded. Then the DS and DI registers have to be initialized. Finally, the CW and the initial count can be written to the timer and the timer will count down for 0.001504 seconds again. This accounts for the difference of the 98 or so CPU clock cycles between 0.000154 seconds and 0.00017 seconds.

Figure 18 (Page 60) is a copy of a Polaroid picture of the oscilloscope trace of *chip select* on the 40000-7FFFF, low byte memory SRAM. It shows the previously mentioned edge spikes very clearly. It also shows one cycle of a repeating pattern. There are 12 chip selects per cycle. This is expected. If one looks at the ISR code in the appendix which is run from memory location 40000h to 4001Dh, one will see there are 12 separate reads of code (a word at a time) between op code executions, i.e.:

.	BA 06	1
	02 B0	
	(BA 06 02)-->LOAD DX with 0206	
.	B0 EE	2
	(B0 B0)----->Load AL with B0	
	(EE)----->Write AL to counter 2	
.	BA 04	3
	02 B8	
	(BA 02 04)-->LOAD DX with 0204	
.	2F 00	4
	(B8 2F 00)-->Load AX with 002F	

•	EF B0	5
	(EF)----->Write to counter 2 with 002F	
•	08 48	6
	(B0 08)----->Load AL with 8	
	(48)----->Decrement AX	
•	3C 00	7
	(3C 00)----->Compare AL with 0	
•	EB 49	8
	(EB 49)----->Jump back 7 to code 48	
•	74 02	9
	(74 02)----->Jump to next code if AL = 0	
•	BA 00	10
	01 B0	
	(BA 00 01)--->Load DX with 0100	
•	20 EE	11
	(B0 20)----->Load AL with 20	
	(EE)----->Write AL to 8259	
•	CF FB	12
	(FB)----->Enable interrupts	
	(CF)----->Return from ISR	

These 12 separate reads correspond to the 12 chip selects shown in the figure. (Probably not in this order.) This gives an example of the kind of procedure(s) followed to verify proper circuit operation.

Finally, for the third increment, a program was again written to repetitively output a stored character directly to the SCC. (See Appendix H.) This program was tried and it could not be made to work. The circuit, or the oscilloscope triggering, was just too unstable. Perhaps the program was incorrect (not likely because only a very small new part was added), or perhaps it was a function of some kind of performance margin being exceeded with respect to the SRAM memory. This problem would take too much time to solve without more advanced monitoring tools. The implementation of the host and target monitor system already mentioned

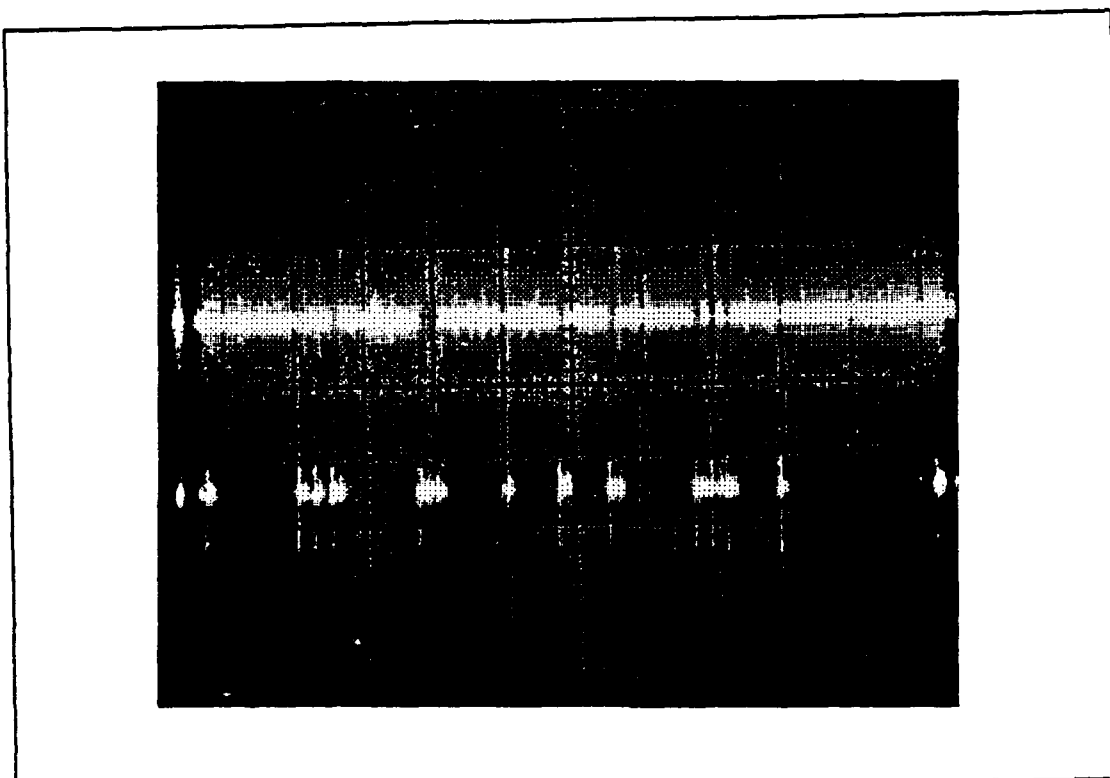


Figure 18. Interrupt Controller Test--Increment 2

should settle the issue. However, the interrupt controller was already shown to work, so a program was written to test just the SCC by itself to complete the hardware verification.

#### 7. Serial Communications Controller (SCC)

The last program, to test the SCC, is shown in Appendix I. The CPU sends a character to the SCC's transmit buffer and the SCC is (or should be) programmed to put the character out at 9600 baud. For the first part of the program, the SCC is initialized to transmit the character at 9600 baud. Then, after the CPU reads the character from memory and loads it into the SCC's transmit buffer, the CPU keeps polling the SCC until it finds the SCC transmit buffer

empty. When the CPU finds the buffer empty, it sends the SCC the same character from memory again and the process repeats.

One should detect a single character stream from the SCC at 9600 baud. A CRT was procured to hook up to the RS-232 port so the character could possibly be seen on the CRT screen. It was not clear from the data sheets available on the 85C30 SCC in the component catalog [Ref. 26] exactly how to set all the bits in the various control registers. The program in the appendix could not be made to work. (A Zilog technical representative was contacted and he explained it was very difficult to program the SCC with only the component description in the component catalog. He said he would be mailing the proper information. [Ref. 27])

Then the error was discovered. The final "EE" in the write registers initialization sequence had been inadvertently left off, so of course the baud rate generator was not enabled. This was corrected, and then one could see the *serial data out* pin going high and low at some changing frequency. One could only get a flash of the pulse as it periodically traversed the oscilloscope screen. This inability to lock on the signal is most likely caused by the character being put out at slightly different times on each pass. The CPU is so fast in executing the Tx buffer empty check loop that an inconsistent number of loops is probably performed each time before the next character is fetched and loaded in the SCC transmit buffer. Figures 19 and 20 on the





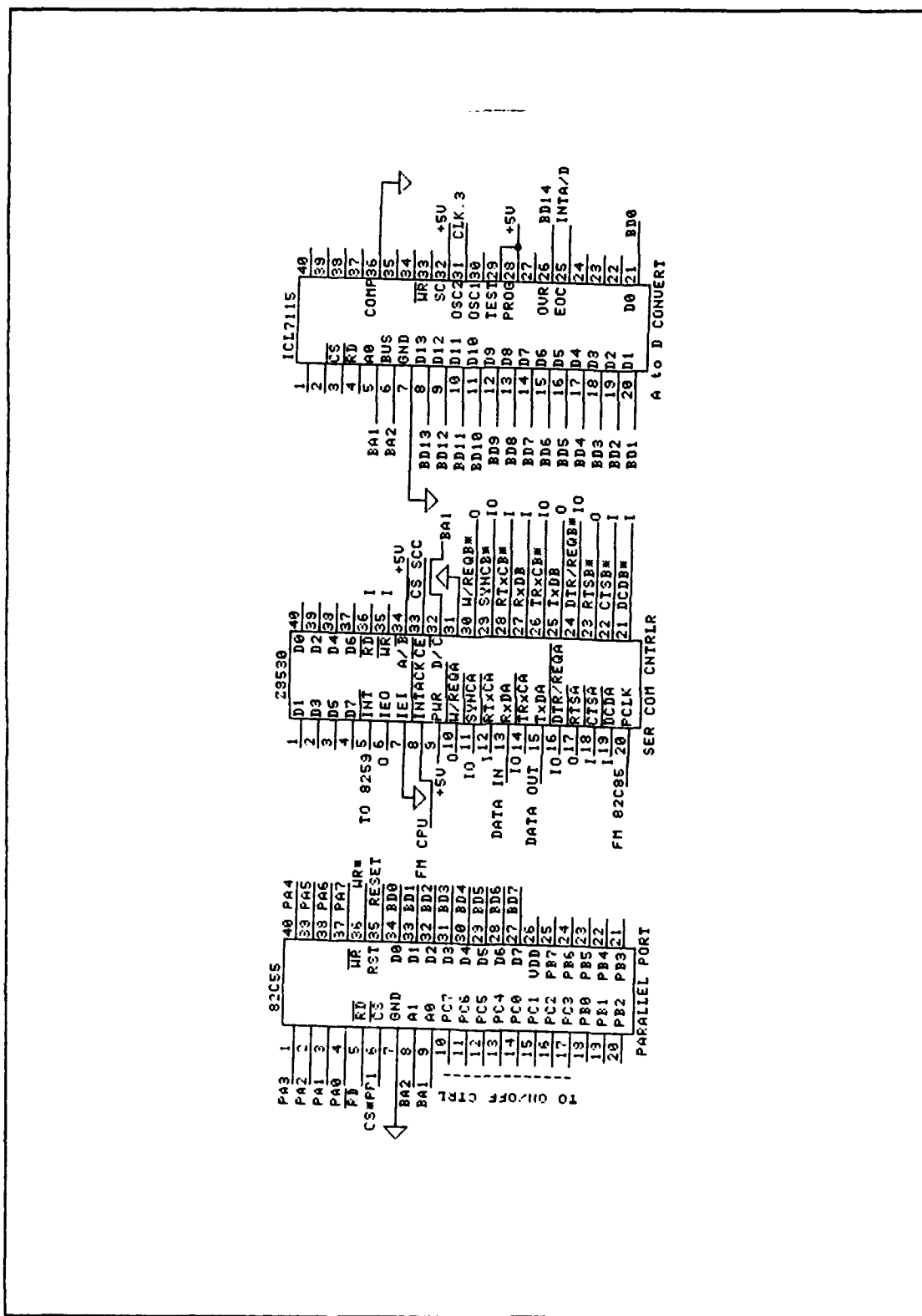


Figure 20. Complete Circuit Schematic--Peripherals

last two pages, in conjunction with Figure 14, constitute the entire computer system in schematic form.

All the components of the system have been shown to work as expected. The oscilloscope has been used to verify correct circuit operation for the complete system.

#### **IV. RECOMMENDATIONS FOR FURTHER WORK**

##### **A. WRITE A CHARACTER TO THE CRT**

This should be the next step, to verify the capability of correct operation of the SCC within the circuit. The program in Appendix I should give the next person to continue with this open ended project a good base with which to begin.

The following recommended actions are not necessarily in temporal or priority order. However, implementation of this CRT step will be instrumental in the next recommended step.

##### **B. INSTALL HOST-TO-TARGET MONITOR PROGRAM**

This will make the job of writing test programs much easier. An assembler or compiler can be used and the program code can be loaded directly to SRAM or into a file which can then be more quickly burned into the EPROM. An assembler could have been used for the present effort, but it was felt that the programs at this level were simple enough that the extra time it would have taken to implement an assembler could be better spent in coding the short programs directly.

##### **C. WRITE OPERATING SYSTEM BOOTSTRAP KERNEL**

This assumes that the operating system and application programs should be capable of being loaded from the ground. It is possible, though not likely, that a decision could be

made that all programs will reside in ROM. If so, then SRAM will be used only for messages (and possibly telemetry data).

#### **D. IMPLEMENT AX.25 PROTOCOL**

Whether the AX.25 protocol resides in ROM or SRAM, its programming and validation will be an extensive project. There will probably have to be close coordination with the person overseeing the PANSAT communications subsystem at that time.

#### **E. IMPLEMENT RESET**

Experience in the laboratory has shown that this is one of the most important required external commands. If the computer system gets hit by a cosmic ray in the wrong place, or otherwise locks up or goes into an invalid state, there must be a way to force the system back to a known state. Hence the need for reset.

#### **F. IDENTIFY OTHER REQUIREMENTS AND BEGIN HARDWARE OR SOFTWARE MODIFICATIONS**

A partial list of other possible required tasks on the road to a fully functional flight-ready communications controller and processor are:

- Identify and implement any other required external commands
- Identify and incorporate need, if any, for backup batteries
- Identify any time critical housekeeping tasks
- Identify need for A/D converter and/or parallel port

# APPENDIX A

## Instruction Set Summary

### 8086 INSTRUCTION SET

#### CONTROL TRANSFER

##### CALL - Call:

Direct within segment

Indirect within segment

Direct intersegment

Indirect intersegment

##### JMP - Unconditional Jump

Direct within segment

Direct within segment short

Indirect within segment

Direct intersegment

Indirect intersegment

##### RET - Return from CALL

Within segment

Within seg adding return to SP

Intersegment

Intersegment adding immediate to SP

JL/JLE - Jump on less/equal zero

JL/JGTE - Jump on less/not greater or equal

JLE/JGE - Jump on less or equal/not greater

JG/JGE - Jump on below/not above or equal

JGE/JLE - Jump on below or equal/not above

JL/JPL - Jump on carry/parity even

JO - Jump on overflow

JS - Jump on sign

JNE/JNZ - Jump on not equal/not zero

JNL/JNL - Jump on not less/greater or equal

JNL/JNL - Jump on not less or equal/greater

70543210 70543210 70543210

11101000 disp low disp high

11111111 mod 010 r/m

10011010 offset low offset high

seg low seg high

11111111 mod 011 r/m

11101001 disp low disp high

11101011 disp

11111111 mod 100 r/m

11101010 offset low offset high

seg low seg high

11111111 mod 101 r/m

11000011

11000010 data low data high

11001011

11001010 data low data high

01101000 disp

01101001 disp

01101010 disp

01101011 disp

01101100 disp

01101101 disp

01101110 disp

01101111 disp

01110000 disp

01110001 disp

01110010 disp

01110011 disp

JNB/JNB - Jump on not below/above or equal

JNBE/JNBE - Jump on not below or equal/above

JNP/JNP - Jump on not parity odd

JO - Jump on not overflow

JS - Jump on not sign

LOOP - Loop CX times

LOOPE/LOOPF - Loop while not equal

LOOPL/LOOPL - Loop while not less/equal

JECXZ - Jump on CX zero

#### INT - Interrupt

Type specified

Type 3

INT0 Interrupt on overflow

INT1 Interrupt return

70543210 70543210

01100011 disp

01100111 disp

01101011 disp

01100001 disp

01110001 disp

11100010 disp

11100001 disp

11100000 disp

11100001 disp

11001011 type

11001100

11001110

11001111

#### PROCESSOR CONTROL

CIC Clear carry

CNC Complement carry

STC Set carry

CLD Clear direction

STD Set direction

CLI Clear interrupt

STI Set interrupt

HLT Halt

WAIT Wait

ESC Escape no external device

LOCK Bus lock prehe

11110000

11110101

11110001

11111100

11111101

11111010

11111011

11110100

10011011

10011011 mod = s r/m

11110000

#### Footnotes:

AL = 8-bit accumulator

AX = 16-bit accumulator

CX = Count register

DS = Data segment

ES = Extra segment

Above/below refers to unsigned value

Greater = more positive

Less = less positive (more negative) signed values

d = 1 then "to" reg; if d = 0 then "from" reg

d = 1 then word instruction; if d = 0 then byte instruction

if s w = 01 then 16 bits of immediate data form the operand

if s w = 11 then an immediate data byte is sign extended to

form the 16-bit operand

if v = 0 then "count" = 1, if v = 1 then "count" in (CL)

x = don't care

z is used for string primitives for comparison with ZF FLAG

#### SEGMENT OVERRIDE PREFIX

001 reg 110

if mod = 11 then r/m is treated as a REG field

if mod = 00 then DISP = 3, disp-low and disp-high are absent

if mod = 01 then DISP = disp-low sign-extended to 16-bits, disp-high is absent

if mod = 10 then DISP = disp-high disp-low

if r/m = 000 then EA = (BX) + (SI) + DISP

if r/m = 001 then EA = (BX) + (DI) + DISP

if r/m = 010 then EA = (BP) + (SI) + DISP

if r/m = 011 then EA = (BP) + (DI) + DISP

if r/m = 100 then EA = (SI) + DISP

if r/m = 101 then EA = (DI) + DISP

if r/m = 110 then EA = (BP) + DISP

if r/m = 111 then EA = (BX) + DISP

DISP follows 2nd byte of instruction (before data if required)

\*except if mod = 00 and r/m = 110 then EA = disp-high disp-low

Mnemonics © Intel, 1978

REG is assigned according to the following table

10-Bit [w = 1]	8-Bit [w = 0]	Segment
000 AX	000 AL	00 ES
001 CX	001 CL	01 CS
010 DX	010 DL	10 SS
011 BX	011 BL	11 DS
100 SP	100 AH	
101 BP	101 CH	
110 SI	110 BH	
111 DI	111 DH	

Instructions which reference the flag register use the symbol FLAGS to represent the file

FLAGS = X X X X (OF) (IF) (TF) (SF) (ZF) X (AF) X (PF) X (CF)

## Instruction Set Summary

### DATA TRANSFER

#### MOV - Move

Register-memory to register	10001000	mod reg r/m			
Immediate to register-memory	11000110	mod 000 r/m	data	data d = 1	
Immediate to register	10110100	reg	data	data d = 1	
Memory to accumulator	10100000	add low	add high		
Accumulator to memory	10100010	add low	add high		
Register-memory to register-memory	10001110	mod 0 reg r/m			
Segment register to register-memory	10001100	mod 0 reg r/m			

#### POPB - Push

Register-memory	11110110	mod 110 r/m			
Register	01101000	reg			
Segment register	00011100	reg			

#### POP - Pop

Register-memory	10001111	mod 000 r/m			
Register	01011000	reg			
Segment register	00011111	reg			

#### SCAS - Compare

Register-memory with register	10000110	mod reg r/m			
Register with accumulator	10010100	reg			

#### ST - Store

Fixed port	11100100	port			
Variable port	11100110	port			

#### OUT - Output to

Fixed port	11100110	port			
Variable port	11100100	port			

#### HLT - Halt

Register-memory	10001001	mod reg r/m			
Register	10001011	mod reg r/m			
Segment register	10001000	mod reg r/m			

#### LOD - Load

Register-memory	10001001	mod reg r/m			
Register	10001011	mod reg r/m			
Segment register	10001000	mod reg r/m			

#### STOS - Store

Register-memory	10001001	mod reg r/m			
Register	10001011	mod reg r/m			
Segment register	10001000	mod reg r/m			

### ARITHMETIC

#### ADD - Add

Register-memory with register to add	00000000	mod reg r/m			
Immediate to register-memory	10000010	mod 000 r/m	data	data d = 1	
Immediate to accumulator	00000010	data	data d = 1		

#### ADC - Add with carry

Register-memory with register to add	00010000	mod reg r/m			
Immediate to register-memory	10000010	mod 010 r/m	data	data d = 01	
Immediate to accumulator	00010010	data	data d = 1		

#### INC - Increment

Register-memory	11111110	mod 000 r/m			
Register	01000100	reg			
ADD-ASCII adjust for add	00101011				
DAI-Decimal adjust for add	00100111				

#### DEC - Decrement

Register-memory with register to subtract	00101000	mod reg r/m			
Immediate to register-memory	10000010	mod 010 r/m	data	data d = 01	
Immediate to accumulator	00101010	data	data d = 1		

#### DEC - Decrement with borrow

Register-memory with register to subtract	00011000	mod reg r/m			
Immediate to register-memory	10000010	mod 011 r/m	data	data d = 01	
Immediate to accumulator	00011010	data	data d = 1		

Mnemonics Intel, 1978

### DEC - Decrement

Register-memory	11111110	mod 001 r/m			
Register	01000100	reg			
DEC-Change sign	11110110	mod 011 r/m			

### CMPS - Compare

Register-memory and register	00110000	mod reg r/m			
Immediate with register-memory	10000010	mod 111 r/m	data	data d = 01	
Immediate with accumulator	00110010	data	data d = 1		
ADD-ASCII adjust for subtract	00110111				
DAI-Decimal adjust for subtract	00110101				
MUL-Multiply register-memory	11110110	mod 100 r/m			
MUL-Multiply register-memory	11110110	mod 101 r/m			
ADD-ASCII adjust for multiply	11110100	mod 000 r/m			
IMUL-Integer multiply	11110110	mod 110 r/m			
IMUL-Integer divide register-memory	11110110	mod 111 r/m			
ADD-ASCII adjust for divide	11110101	mod 010 r/m			
CDQ-Convert byte to word	10011000				
CWD-Convert word to double word	10011001				

### LOGIC

NOT-Invert	11110110	mod 010 r/m			
SHL/SHR-Shift right or left	11010000	mod 100 r/m			
SHL-Shift right or left	11010000	mod 101 r/m			
SHR-Shift right	11010000	mod 111 r/m			
SHL-Shift left	11010000	mod 000 r/m			
SHR-Shift right	11010000	mod 001 r/m			
ROL-Rotate through carry flag left	11010000	mod 010 r/m			
ROR-Rotate through carry flag right	11010000	mod 011 r/m			

### AND - And

Register-memory and register to other	00100000	mod reg r/m			
Immediate to register-memory	10000010	mod 000 r/m	data	data d = 1	
Immediate to accumulator	00100010	data	data d = 1		

### TEST - And function in flag as result

Register-memory and register	10000010	mod reg r/m			
Immediate data and register-memory	11110110	mod 000 r/m	data	data d = 1	
Immediate data and accumulator	10101010	data	data d = 1		

### OR - Or

Register-memory and register to other	00001000	mod reg r/m			
Immediate to register-memory	10000010	mod 001 r/m	data	data d = 1	
Immediate to accumulator	00001010	data	data d = 1		

### XOR - Exclusive or

Register-memory and register to other	00110000	mod reg r/m			
Immediate to register-memory	10000010	mod 110 r/m	data	data d = 1	
Immediate to accumulator	00110010	data	data d = 1		

### STORE MANIPULATION

REP-Repeat	11110011				
SCAS-Scan by forward	10100100				
CMPS-Compare by forward	10100110				
SCAS-Scan by backward	10100101				
CMPS-Compare by backward	10100111				
STOS-Store by forward	10100100				
STOS-Store by backward	10100101				

[Ref. 25: pp. 4-76--4-77]

## APPENDIX B

### INITIAL CIRCUIT TEST PROGRAM

The program continuously jumps to itself at starting address FFFF0h.

8086 ADDR		LO BYTE EPROM ADDR	HI BYTE EPROM ADDR	
FFFF4	FF	1FFFA		_____ ; Jmp to FFFF0
FFFF3	FF		1FFF9	_____ ;
FFFF2	00	1FFF9		_____ ;
FFFF1	00		1FFF8	_____ ;
FFFF0	EA	1FFF8		_____ ; <---(Pwr on rst jmp)

## APPENDIX C

### INITIAL MEMORY TEST PROGRAM

Program continuously writes the arbitrary number "5" to arbitrary SRAM memory location BFFF0.

8086 ADDR		LO BYTE EPROM ADDR	HI BYTE EPROM ADDR	
FFFF4	FF	1FFFA		;Jmp to FFFDC
FFFF3	FD	1FFF9		;
FFFF2	00	1FFF9		;
FFFF1	0C	1FFF8		;
FFFF0	EA	1FFF8		; <---(Pwr on rst jmp)
FFFEF	FF	1FFF7		;Jmp to FFFF0
FFFEF	FF	1FFF7		;
FFFEF	00	1FFF6		;
FFFEF	00	1FFF6		;
FFFEF	EA	1FFF5		;
FFFEA	14	1FFF5		;Mov B fm M[BFFF0] to DL
				;register
FFFE9	8A	1FFF4		;
FFFE8	90	1FFF4		;NOP
FFFE7	05	1FFF3		;Mov B immed #05 to
				;M[BFFF0]
FFFE6	04	1FFF3		; (M[BFFFx4 + 0 = BFFF0])
FFFE5	C6	1FFF2		;
FFFE4	00	1FFF2		;Mov W immed #0000 to SI
				;register
FFFE3	00	1FFF1		;
FFFE2	BE	1FFF1		;
FFFE1	DE	1FFF0		;Mov W SI reg to DS seg
				;register
FFFE0	8E	1FFF0		;
FFFD F	BF	1FFE F		;Mov W immed #BFFF to SI
				;register
FFFD E	FF	1FFE F		;
FFFD D	C6	1FFEE		;
FFFD C	C7	1FFEE		;



## APPENDIX D

### MEMORY/IO TEST PROGRAM

Program to verify that the CPU asserts IO\* of the M/IO\* signal when writing to a variable port--in this case pin 10 (Y5) on the IO chip select Decoder. It was written because the program to load the 82C53 (cheap prototype replacement for the 82C54) with a control word (Mode 3) and an initial count (04) didn't appear to be working. To eliminate the M/IO\* select circuitry as the culprit, this program tests to make sure IO\* is asserted when OUT writes to a variable port. The proper *chip select* line is asserted.

8086 ADDR	LO BYTE EPROM ADDR	HI BYTE EPROM ADDR	
FFFF4	FF	1FFFA	_____ ;Jmp to FFFE8
FFFF3	F0	1FFF9	_____ ;
FFFF2	00	1FFF9	_____ ;
FFFF1	E8	1FFF8	_____ ;
FFFF0	EA	1FFF8	_____ ; <---(Pwr on rst jmp)
FFFEF	EE	1FFF7	_____ ;OUT to [port DX] with
			_____ ;(AL)
FFFE6	FF	1FFF7	_____ ;Load AL with #FF
FFFE5	C0	1FFF6	_____ ;
FFFE4	C6	1FFF6	_____ ;
FFFE3	02	1FFF5	_____ ;Load DX with #0280 (Port
			_____ ;"5")
FFFE2	80	1FFF5	_____ ;A11A10A9A8A7A6A5A4A3A2A1A0
FFFE1	C2	1FFF4	_____ ; X 0 1 0 1 X X X X 0 0 X
			_____ ;
			_____ ; 2   8   0
FFFE0	C7	1FFF4	_____ ;

Line Y5 is asserted, as expected, when IO\* of M/IO\* is asserted.

## APPENDIX E

## INITIAL 82C54 TIMER TEST PROGRAM

The program loads the 82C54 (or '53) timer (counter 2) with a control word (byte) indicating mode 3 (square wave generator) with a period loaded as an initial count, in this case "4". The timer's cycle, therefore, is 1/4 of the input clock's, or 1/4 of 0.3125 MHz = 78.125 kHz.

8086 ADDR		LO BYTE EPROM ADDR	HI BYTE EPROM ADDR	
FFFF4	FF	1FFFA		;Jmp to FFFDB
FFFF3	F0		1FFF9	;
FFFF2	00	1FFF9		;
FFFF1	DB		1FFF8	;
FFFF0	EA	1FFF8		; <---(Pwr on rst jmp)
FFFEF	FF		1FFF7	;Jmp to FFFEB-->
				;Continuous loop--
FFFE E	F0	1FFF7		;timer set
FFFE D	00		1FFF6	;(Jmp to FFFDB-keep
				;setting the timer,
FFFE C	EB (DB)	1FFF6		;over and over)
FFFE B	EA		1FFF5	;
FFFE A	EE	1FFF5		;OUT to [DX port] with
				;(AL=04)--port addr
				;is Y4 (Timer)
				____;Load cntr 2 with init
				;count
FFFE 9	02		1FFF4	;Load DX with #027C*
FFFE 8	7C	1FFF4		;A11A10A9A8A7A6A5A4A3A2A1A0
FFFE 7	C2		1FFF3	; X 0 1 0 0 X X X X 1 0 X
				;
				;
				2 7 C
				;Port Y4, load into cntr
				;2 init value (in AL)
FFFE 6	C7	1FFF3		;
FFFE 5	04		1FFF2	;Load AL with #04*
FFFE 4	C0	1FFF2		;(Initial counter value)
FFFE 3	C6		1FFF1	;
FFFE 2	EE	1FFF1		;OUT to [DX port] with
				;(AL = 96)--Control word
				;(AL) selects cntr 2,
				;Mode 3

FFFE1		96	1FFF0	;Load AL with #96*
FFFE0	C0		1FFF0	;Cntr 2, LSB, Mode3,
				;Binary cnt
FFFDf		C6	1FFEF_____	;
FFFDE	02		1FFEF	;Load DX with #027E*
FFFDD	7E		1FFEE	;A11A10A9A8A7A6A5A4A3A2A1A0
FFFDC	C2		1FFEE	; 0 0 1 0 0 X X X X 1 1 X
				;
				; 2 7 E
				;Port Y4 (Timer), write
				;cntrl "word" (to come
FFFDB		C7	1FFED_____	;from AL)

26 bytes

\*The 2 byte opcode loads of DX (C7 C2) and AL (C6 C0) can be replaced by the 1 byte opcodes BA and B0, respectively.

## APPENDIX F

### INTRPT CNTRLR TEST PROGRAM: INCREMENT 1

This program only tests the 8254 timer in mode 0 as a prelude to the full-blown interrupt controller test program (iteration 3).

First, it was verified that the timer could be programmed to time out and go high while the CPU was doing a loop for a certain number of iterations. The address and data lines and the timing relationships were as expected.

The data sheet on the 8254 timer is wrong. It said that once the timer times out in Mode 0, one needs only to reload the CW or reload the count and the timer will resume counting. Evidently, one needs to reload both the CW and the initial count, as in this program, for the counter to resume counting.

The code is read from bottom to top.

8086 ADDR		LO BYTE EPROM ADDR	HI BYTE EPROM ADDR	
FFFF4	FF	1FFFA		;Jmp to FFFCA
FFFF3	F0		1FFF9	;
FFFF2	00	1FFF9		;
FFFF1	CA		1FFF8	;
FFFF0	EA	1FFF8		; <---(Pwr on rst jmp)
FFFEF	FF		1FFF7	;Jmp to FFFD6
FFFEF	F0	1FFF7		;(Reset timer after AX
FFFEF	00		1FFF6	;counts down from 127d)
FFFEF	D6	1FFF6		;
FFFEF	EA		1FFF5	;
FFFEA	EE	1FFF5		;Write init cnt (02) to
FFFE9	02		1FFF4	;timer; Load AL with init
FFFE8	B0	1FFF4		;count = 02
FFFE7	02		1FFF3	;Move #0204 to DX reg
FFFE6	04	1FFF3		;Cntr 2 is to be loaded
FFFE5	BA		1FFF2	;with initial count
FFFE4	EE	1FFF2		;Write cntrl W (90) to
				;timer
FFFE3	90		1FFF1	;Load AL with CW = 90
FFFE2	B0	1FFF1		;(Mode 0, LSB, cntr 2)

FFFE1	02		1FFF0	;Move #0206 to DX
FFFE0	06			;register
FFFDF	BA	1FFF0		;The CW in AL is to be
			1FFEF	;written to the cntr 2 CW
				;register
FFFDE	F9	1FFEF		;Else, Short Jump to
				;FFFD8 to decrement
FFFD5	EB		1FFEE	;AX again (F9 = -7d)
FFFD4	02	1FFEE		;If AX = 0, jump 2
FFFD3	74		1FFED	;addresses, to FFFDF
FFFDA	00	1FFED		;CMP AX with 0
FFFD9	3C		1FFEC	;
FFFD8	48	1FFEC		;Decrement AX
FFFD7	7F		1FFEB	;Load AX with 127d
FFFD6	B0	1FFEB		;
				;OUT initial count to
FFFD5	EE		1FFEA	;counter 2
FFFD4	02	1FFEA		;Load initial count of 2
FFFD3	B0		1FFE9	;into AL
FFFD2	02	1FFE9		;Load DX with #0204 for
FFFD1	04		1FFE8	;timer initial count
FFFD0	BA	1FFE8		;(from AL to be loaded)
FFFCF	EE		1FFE7	;OUT the CW to the timer
FFFCF	90	1FFE7		;Load the CW for Mode 0,
FFFCF	B0		1FFE6	;LSB, counter 2 into AL
FFFCF	02	1FFE6		;Ld DX with #0206 for
FFFCB	06		1FFE5	;selecting timer, write
FFFCB	BA	1FFE5		;CW (with CW in AL)

43 bytes

## APPENDIX G

### INTRPT CNTRLR TEST PROGRAM: INCREMENT 2

In step one, it was verified that the timer could be programmed to run in Mode 0. When *OUT2* on the 8254 went high it stayed high until the timer was reset. The timer was reset only after the CPU looped for a large number of iterations. When the CPU was done, it reset the timer and the process was continually repeated.

In this iteration, when the timer times out, *OUT2* is used as a signal to the 8259 on *IR3* that there is an interrupt to be serviced. The 8259 alerts the CPU with the *INT* line. The CPU replies with *INTA\** and the 8259 gives the CPU the address of where to look for the address of the interrupt service routine (ISR). (The ISR address and the ISR itself have to have been first loaded into memory.) The ISR just resets the timer.

The code is read from bottom to top.

8086 ADDR	LO BYTE EPROM ADDR	HI BYTE EPROM ADDR	
FFFF4	FF	1FFFA	_____ ;Jump to FFF61
FFFF3	F0	1FFF9	_____ ;
FFFF2	00	1FFF9	_____ ;
FFFF1	61	1FFF8	_____ ;
FFFF0	EA	1FFF8	_____ ; <---(Pwr on rst jmp)
FFFEF	FF	1FFF7	_____ ;Jump to FFFEB
FFFEF	F0	1FFF7	_____ ;The CPU stays here until
FFFEF	00	1FFF6	_____ ;it's interrupted
FFFEF	EB	1FFF6	_____ ;
FFFEF	EA	1FFF5	_____ ;
FFFEA	FB	1FFF5	_____ ;Enable interrupts

Load the interrupt service routine. The ISR resets the timer and clears the highest priority ISR bit in the 8259 (there is only one in this case). Because the 8259 runs at 2.5 MHz and the timer only runs at .3125 MHz, there is a little delay loop to make sure the timer has gone low after being reset before the ISR bit is reset and interrupts are again enabled.

The delay loop is almost certainly not required, but it doesn't hurt to have it.

FFFE9		CF	1FFF4	_____	;Code CF-->return from
FFFE8	FB		1FFF4	_____	;ISR; Code FB-->Enable
FFFE7		05	1FFF3	_____	;interrupts
FFFE6	C7		1FFF3	_____	;
FFFE5		47	1FFF2	_____	;
FFFE4	47		1FFF2	_____	;
FFFE3		EE	1FFF1	_____	;Code EE-->OUT to reset
				_____	;ISR bit
FFFE2	20		1FFF1	_____	;Code B0 20-->Load AL
				_____	;with 20 ("20" for OCW2
FFFE1		05	1FFF0	_____	;will reset highest
FFFE0	C7		1FFF0	_____	;priority ISR bit)
FFFD9		47	1FFEF	_____	;
FFFD8	47		1FFEF	_____	;
FFFD7		B0	1FFEE	_____	;Code BA 00 01-->Load DX
FFFD6	BA		1FFEE	_____	;with addr to write OCW2
FFFD5		05	1FFED	_____	;to 8259 to reset ISR bit
FFFD4	C7		1FFED	_____	;for IR3; (OUT2 has had
FFFD3		47		_____	;plenty of time to go low
FFFD2	47			_____	;because AX counted down
FFFD1		F9	1FFEC	_____	;from 8)
FFFD0	EB		1FFEB	_____	;
FFFCF		05	1FFEB	_____	;
FFFC8	C7		1FFEA	_____	;
FFFC7		47	1FFEA	_____	;
FFFC6	47		1FFE9	_____	;
FFFC5		00	1FFE9	_____	;
FFFC4	3C		1FFE8	_____	;Code EB 49-->Jump back 7
FFFC3		05	1FFE8	_____	;counts to opcode 48 to
FFFC2	C7		1FFE7	_____	;decrement AX again
FFFC1	47		1FFE7	_____	;
FFFC0		02	1FFE6	_____	;
			1FFE6	_____	;
		74	1FFE5	_____	;Code 74 02-->If AX was 0
		05	1FFE5	_____	;then jump forward 2
		C7	1FFE4	_____	;counts to BA opcode;
		47	1FFE4	_____	;else, go to next opcode:
			1FFE3	_____	;EB
		00	1FFE3	_____	;
		3C	1FFE2	_____	;Code 3C 00-->CMP AX with
		05	1FFE2	_____	;0
			1FFE1	_____	;
		C7	1FFE1	_____	;
		47	1FFE0	_____	;
			1FFE0	_____	;

FFFBF	48	1FFDF	;Code B0 08--Load AL with
FFFB E	08	1FFDF	;8
FFFB D	05	1FFDE	;Code 48-->Decrement AX
FFFB C	C7	1FFDE	;
FFFB B	47	1FFDD	;
FFFB A	47	1FFDD	;
FFFB 9	B0	1FFDC	;Code EF-->OUT with
FFFB 8	EF	1FFDC	;initial count to
FFFB 7	05	1FFDB	;cntr 2
FFFB 6	C7	1FFDB	;
FFFB 5	47	1FFDA	;
FFFB 4	47	1FFDA	;
FFFB 3	00	1FFD9	;Code B8 2F 00-->load AX
FFFB 2	2F	1FFD9	;with 00 2F as initial
FFFB 1	05	1FFD8	;count
FFFB 0	C7	1FFD8	;
FFFA F	47	1FFD7	;
FFFA E	47	1FFD7	;
FFFA D	B8	1FFD6	;Code BA 04 02-->Load DX
FFFA C	02	1FFD6	;with addr to load the
FFFA B	05	1FFD5	;cntr 2 with the initial
FFFA A	C7	1FFD5	;word size count (from
			;AX)
FFFA 9	47	1FFD4	;
FFFA 8	47	1FFD4	;
FFFA 7	04	1FFD3	;
FFFA 6	BA	1FFD3	;
FFFA 5	05	1FFD2	;
FFFA 4	C7	1FFD2	;
FFFA 3	47	1FFD1	;DI = 5
FFFA 2	47	1FFD1	;
FFFA 1	EE	1FFD0	;Code B0 B0-->load AL
FFFA 0	B0	1FFD0	;with cntr 2 CW, Mode 0,
FFF9 F	05	1FFCF	;word size initial count
FFF9 E	C7	1FFCF	;Code EE-->WR the CW B0
			;to AL)
FFF9 D	47	1FFCE	;DI = 4
FFF9 C	47	1FFCE	;
FFF9 B	B0	1FFCD	;Move code "02 B0" to
			;M[DS + DI]
FFF9 A	02	1FFCD	; = M[40002]
FFF9 9	05	1FFCC	;Code "BA 06 02"-->Load
FFF9 8	C7	1FFCC	;DX with addr where to ld
			;AL cntr 2 CW
FFF9 7	47	1FFCB	;Increment DI-->DI = 2
FFF9 6	47	1FFCB	;Increment DI-->DI = 1
FFF9 5	06	1FFCA	;Move code "BA 06" to [DS
FFF9 4	BA	1FFCA	;+ DI = M[4000(0)]
FFF9 3	05	1FFC9	;
FFF9 2	C7	1FFC9	;
FFF9 1	00	1FFC8	;Move 00 00 TO DI reg



```

FFF90 00      1FFC8      ;
FFF8F      BF      1FFC7      ;
FFF8E D8      1FFC7      ;Move (AX) to DS reg
FFF8D      8E      1FFC6      ;
FFF8C 40      1FFC6      ;Load AX with 40 00
FFF8B      00      1FFC5      ;
FFF8A B8      1FFC5      ;

```

Load the address of the ISR in the location for external interrupt number 3 (0008C to 0008F) and initialize the stack segment and the stack pointer.

```

FFF89      FF      1FFC4      ;Move FF FF to SP
FFF88 FF      1FFC4      ;
FFF87      BC      1FFC3      ;
FFF86 D0      1FFC3      ;Move (AX) to SS reg
FFF85      8E      1FFC2      ;
FFF84 50      1FFC2      ;Load AX with 50 00
FFF83      00      1FFC1      ;
FFF82 B8      1FFC1      ;
FFF81      40      1FFC0      ;Move 40 00 to EA =
FFF80 00      1FFC0      ;[DS + DI] = [0 + 8E]
FFF7F      05      1FFBF      ;(CS = 4000(0), IP =
FFF7E C7      1FFBF      ;0000; ISR addr loaded)
FFF7D      00      1FFBE      ;Move 00 8E to DI reg
FFF7C 8E      1FFBE      ;
FFF7B      BF      1FFBD      ;
FFF7A 00      1FFBD      ;Move 00 00 to EA =
FFF79      00      1FFBC      ;[DS + DI] = [0 + 8C]
FFF78 05      1FFBC      ;(IP for ISR = 0000)
FFF77      C7      1FFBB      ;
FFF76 00      1FFBB      ;Move 00 8C to DI reg
FFF75      8C      1FFBA      ;(ISR addr will be at
FFF74 BF      1FFBA      ;0008C through 0008F)
FFF73 D8      1FFB9      ;Move AX to DS register
FFF72 8E      1FFB9      ;
FFF71      00      1FFB8      ;Load AX with 00 00
FFF70 00      1FFB8      ;
FFF6F      B8      1FFB7      ;

```

Initialize the 82C54 timer for counter 2, Mode 0, with an initial count of FF FF. This should be plenty of time for the ISR address and the ISR itself above to be completely loaded before the timer times out.

```

FFF6E EF      1FFB7      ;LSB, then MSB to cntr 2
FFF6D      FF      1FFB6      ;Load initial count, FF
FFF6C FF      1FFB6      ;FF, into AX
FFF6B      B8      1FFB5      ;

```

FFF6A	02		1FFB5		;Load DX with address for
FFF69		04		1FFB4	;cntr 2 initial count (to
FFF68	BA		1FFB4		;come from AX)
FFF67		EE		1FFB3	;CW to cntr 2
FFF66	B0		1FFB3		;Load CW in AL = B0
FFF65		B0		1FFB2	; (Mode 0,16 bit cnt,
					;cntr 2)
FFF63	02		1FFB2		;Load DX with "address"
FFF62		06		1FFB1	;for counter 2 CW (to
FFF61	BA		1FFB1		;come from AL)

148 bytes

## APPENDIX H

### INTRPT CNTRLR TEST PROGRAM: INCREMENT 3

(Correct operation of this program could not be validated.)

In this iteration, as in the second iteration, when the timer times out, *OUT2* is used as a signal to the 8259 on *IR3* that there is an interrupt to be serviced. The 8259 alerts the CPU with the *INT* line. The CPU replies with *INTA\** and the 8259 gives the CPU the address of where to look for the address of the interrupt service routine (ISR). (The ISR address and the ISR itself have to have been first loaded into memory.)

The difference of this iteration is that the ISR first puts out the byte, previously stored at memory location 40000, to the serial communications controller (SCC). Next, the ISR resets the timer, loops for a short while to give the timer more than enough time to go low, and then resets the 8259. When the timer times out, the ISR is run again. One sees the letter "A" on the SCC data pins every 79, 8254 clock cycles. Each 8254 clock cycle takes 16 system or CPU clock cycles (5MHz) to complete. Thus, one sees the "A" approximately every  $79 \times 16 \times 200$  nanoseconds = 252.8 microseconds. Actually, it takes a little bit longer than this due to the overhead time required to reset the timer.

The code is read from bottom to top.

8086 ADDR	LO BYTE EPROM ADDR	HI BYTE EPROM ADDR	
FFFF4	FF	1FFFA	_____ ; Jmp to FFF30
FFFF3	F0	1FFF9	_____ ;
FFFF2	00	1FFF9	_____ ;
FFFF1	30	1FFF8	_____ ;
FFFF0	EA	1FFF8	_____ ; <---(Pwr on rst jmp)
FFFEF	FF	1FFF7	_____ ; Jmp to FFFEB
FFFE	F0	1FFF7	_____ ; The CPU stays here until
FFFD	00	1FFF6	_____ ; it's interrupted
FFFE	EB	1FFF6	_____ ;
FFFE	EA	1FFF5	_____ ;
FFFEA	FB	1FFF5	_____ ; Enable interrupts

Load the interrupt service routine. The ISR first puts out the byte from memory location 40000 to the SCC. Then it resets the timer and clears the highest priority ISR bit in the 8259 (there is only one in this case). Because the 8259 runs at 2.5 MHz and the timer only runs at .3125 MHz, there is a little delay loop to make sure the timer has gone low after being reset before the ISR bit is reset and interrupts are again enabled. The delay loop is almost certainly not required, but it doesn't hurt to have it.

FFFE9	CF		1FFF4	;Code CF-->return from ;ISR
FFFE8	FB	1FFF4		;Code FB-->Enable
FFFE7	05		1FFF3	;interrupts
FFFE6	C7	1FFF3		
FFFE5	47		1FFF2	
FFFE4	47	1FFF2		
FFFE3	EE		1FFF1	;Code EE-->OUT to reset ;ISR bit
FFFE2	20	1FFF1		;Code B0 20-->Load AL
FFFE1	05		1FFF0	;with 20 ("20" for OCW2
FFFE0	C7	1FFF0		;will reset highest ;priority ISR bit)
FFFD9	47		1FFEF	
FFFD8	47	1FFEF		
FFFD7	B0		1FFEE	;Code BA 00 01-->Load DX
FFFD6	01	1FFEE		;with addr to write OCW2
FFFD5	05		1FFED	;to 8259 to reset ISR bit
FFFD4	C7	1FFED		;for IR3; (OUT2 has had ;plenty of time to go low ;because AX counted down ;from 8)
FFFD3	47		1FFEC	
FFFD2	47	1FFEC		
FFFD1	00		1FFEB	
FFFD0	BA	1FFEB		
FFFCF	05		1FFEA	
FFFC8	C7	1FFEA		
FFFC7	47		1FFE9	
FFFC6	47	1FFE9		
FFFC5	F9		1FFE8	;Code EB 49-->Jump back 7
FFFC4	EB	1FFE8		;counts to opcode 48 to
FFFC3	05		1FFE7	;decrement AX again
FFFC2	C7	1FFE7		
FFFC1	47		1FFE6	
FFFC0	47	1FFE6		
FFFCF	02		1FFE5	;Code 74 02-->If AX was 0
FFFC8	74	1FFE5		;then jump forward 2
FFFC7	05		1FFE4	;counts to BA opcode;

FFFC7		47		1FFE3	_____;
FFFC6	47		1FFE3	_____;	
FFFC5		00		1FFE2	_____;
FFFC4	3C		1FFE2	_____;	Code 3C 00-->CMP AX with
FFFC3		05		1FFE1	_____;
FFFC2	C7		1FFE1	_____;	
FFFC1		47		1FFE0	_____;
FFFC0	47		1FFE0	_____;	
FFFBF		48		1FFDF	_____;
FFBFE	08		1FFDF	_____;	Code B0 08--Load AX with
FFBBD		05		1FFDE	_____;
FFBBC	C7		1FFDE	_____;	Code 48-->Decrement AX
FFBBB		47		1FFDD	_____;
FFBBA	47		1FFDD	_____;	
FFBB9		B0		1FFDC	_____;
FFBB8	EF		1FFDC	_____;	Code EF-->OUT with
FFBB7		05		1FFDB	_____;
FFBB6	C7		1FFDB	_____;	initial count to
FFBB5		47		1FFDA	_____;
FFBB4	47		1FFDA	_____;	cntr 2
FFBB3		00		1FFD9	_____;
FFBB2	4F		1FFD9	_____;	Code B8 2F 00-->load AX
FFBB1		05		1FFD8	_____;
FFBB0	C7		1FFD8	_____;	with 00 4F as initial
FFBAF		47		1FFD7	_____;
FFBAE	47		1FFD7	_____;	count
FFBAD		B8		1FFD6	_____;
FFBAC	02		1FFD6	_____;	Code BA 04 02-->Load DX
FFBAB		05		1FFD5	_____;
FFBAA	C7		1FFD5	_____;	with addr to load the
					cntr 2 with the initial
					word size count (from
					AX)
FFFA9		47		1FFD4	_____;
FFFA8	47		1FFD4	_____;	
FFFA7		04		1FFD3	_____;
FFFA6	BA		1FFD3	_____;	
FFFA5		05		1FFD2	_____;
FFFA4	C7		1FFD2	_____;	
FFFA3		47		1FFD1	_____;
FFFA2	47		1FFD1	_____;	
FFFA1		EE		1FFD0	_____;
FFFA0	B0		1FFD0	_____;	Code B0 B0-->load AL
FFF9F		05		1FFCF	_____;
FFF9E	C7		1FFCF	_____;	with cntr 2 CW, Mode 0,
					word size initial count
					Code EE-->WR the CW B0
					to AL)
FFF9D		47		1FFCE	_____;
FFF9C	47		1FFCE	_____;	
FFF9B		B0		1FFCD	_____;
FFF9A	02		1FFCD	_____;	Code BA 06 02-->Load DX
FFF99		05		1FFCC	_____;
FFF98	C7		1FFCC	_____;	with addr for cntr 2 CW
FFF97		47		1FFCB	_____;
					(from AL)

FFF96	47	1FFCB	_____;
FFF95	06	1FFCA	_____;
FFF94	BA	1FFCA	_____;
FFF93	05	1FFC9	_____;
FFF92	C7	1FFC9	_____;
FFF91	47	1FFC8	_____;
FFF90	47	1FFC8	_____;
FFF8F	EE	1FFC7	_____;
FFF8E	00	1FFC7	_____;
FFF8D	05	1FFC6	_____;
FFF8C	C7	1FFC6	_____;
FFF8B	47	1FFC5	_____;
FFF8A	47	1FFC5	_____;
FFF89	02	1FFC4	_____;
FFF88	BA	1FFC4	_____;
FFF87	05	1FFC3	_____;
FFF86	C7	1FFC3	_____;
FFF85	47	1FFC2	_____;
FFF84	47	1FFC2	_____;
FFF83	05	1FFC1	_____;
FFF82	8A	1FFC1	_____;
FFF81	05	1FFC0	_____;
FFF80	C7	1FFC0	_____;
FFF7F	47	1FFBF	_____;
FFF7E	47	1FFBF	_____;
FFF7D	00	1FFBE	_____;
FFF7C	00	1FFBE	_____;
FFF7B	05	1FFBD	_____;
FFF7A	C7	1FFBD	_____;
FFF79	47	1FFBC	_____;
FFF78	47	1FFBC	_____;
FFF77	BF	1FFBB	_____;
FFF76	D8	1FFBB	_____;
FFF75	05	1FFBA	_____;
FFF74	C7	1FFBA	_____;
FFF73	47	1FFB9	_____;
FFF72	47	1FFB9	_____;
FFF71	8E	1FFB8	_____;
FFF70	40	1FFB8	_____;
FFF6F	05	1FFB7	_____;
FFF6E	C7	1FFB7	_____;
FFF6D	47	1FFB6	_____;
FFF6C	47	1FFB6	_____;
FFF6B	00	1FFB5	_____;
FFF6A	B8	1FFB5	_____;
FFF69	05	1FFB4	_____;
FFF68	C7	1FFB4	_____;
FFF67	00	1FFB3	_____;
FFF66	01	1FFB3	_____;
FFF65	BF	1FFB2	_____;
FFF64	D8	1FFBF	_____;

;Code BA 02 00-->  
 ;Load DX with 0200--  
 ;"addr" of the SCC port  
 ;Code EE-->(AL) to SCC  
 ;Code 8A 05-->  
 ;Move "A" at M[40000]  
 ;to AL register  
 ;Code BF 00 00-->  
 ;Load DI with 0000  
 ;Inc DI  
 ;Inc DI  
 ;Move code "40 8E" to  
 ;M[40003];  
 ;Code B8 00 40-->Load  
 ;AX with 4000  
 ;Inc DI-->DI = 3  
 ;Inc DI-->DI = 2  
 ;Move code "B8 00" to  
 ;M[4000x4 + 1] = 40001  
 ;Move 00 01 TO DI reg  
 ;Move (AX) to DS reg

```

FFF63      8E      1FFB1_____ ;
FFF62  40      1FFB1_____ ;Load AX with 40 00
FFF61      00      1FFB0_____ ;
FFF60  B8      1FFB0_____ ;

```

Load the address of the ISR in the location for external interrupt number 3 (0008C to 0008F) and initialize the stack segment and the stack pointer.

```

FFF5F      FF      1FFAF_____ ;Move FF FF to SP
FFF5E  FF      1FFAF_____ ;
FFF5D      BC      1FFAE_____ ;
FFF5C  D0      1FFAE_____ ;Move (AX) to SS reg
FFF5B      8E      1FFAD_____ ;
FFF5A  50      1FFAD_____ ;Load AX with 50 00
FFF59      00      1FFAC_____ ;
FFF58  B8      1FFAC_____ ;
FFF57      40      1FFAB_____ ;Move 40 00 to EA =
FFF56  00      1FFAB_____ ;[DSx4 + DI] = [0 + 8E]
FFF55      05      1FFAA_____ ;(CS = 4000(0), IP =
FFF54  C7      1FFAA_____ ;0001; ISR addr loaded)
FFF53      00      1FFA9_____ ;Move 00 8E to DI reg
FFF52  8E      1FFA9_____ ;
FFF51      BF      1FFA8_____ ;
FFF50  00      1FFA8_____ ;Move 01 00 to EA =
FFF4F      01      1FFA7_____ ;[DSx4 + DI] = [0 - 8C]
FFF4E  05      1FFA7_____ ;(IP for ISR = 0001)
FFF4D      C7      1FFA6_____ ;
FFF4C  00      1FFA6_____ ;Move 00 8C to DI reg
FFF4B      8C      1FFA5_____ ;(ISR addr will be at
FFF4A  BF      1FFA5_____ ;0008C through 0008F)
FFF49      D8      1FFA4_____ ;Move AX to DS register
FFF48  8E      1FFA4_____ ;
FFF47      00      1FFA3_____ ;Load AX with 00 00
FFF46  00      1FFA3_____ ;
FFF45      B8      1FFA2_____ ;

```

Initialize the 82C54 timer for counter 2, Mode 0, with an initial count of FF FF. This should be plenty of time for the ISR address and the ISR itself above to be completely loaded before the timer times out the first time.

```

FFF44  EF      1FFA2_____ ;LSB, then MSB to cntr 2
FFF43      FF      1FFA1_____ ;Load initial count, FF
FFF42  FF      1FFA1_____ ;FF, into AX
FFF41      B8      1FFA0_____ ;
FFF40  02      1FFA0_____ ;Load DX with address for
FFF3F      04      1FF9F_____ ;cntr 2 initial count (to

```

FFF3E	BA		1FF9F	_____	;come from AX)
FFF3D		EE		1FF9E	_____
FFF3C	B0		1FF9E		;CW to cntr 2
FFF3B		B0			;Load CW in AL = B0
				1FF9D	_____
					;(Mode 0,16 bit cnt,
					;cntr 2}
FFF3A	02		1FF9D		;Load DX with "address"
FFF39		06		1FF9C	_____
FFF38	BA		1FF9C		;for counter 2 CW (to
					;come from AL)

Load the character "A" into memory location [40000].

FFF37		C1		1FF9B	_____	;Write "A" to [DSx4 + DI
FFF36	05		1FF9B			;= 40000] ("A" =
FFF35		C6		1FF9A	_____	;11000001)
FFF34	D8		1FF9A			;Move AX to DS
FFF33		8E		1FF99	_____	;
FFF32	40		1FF99			;Move #4000 to AX
FFF31		00		1FF98	_____	;
FFF30	B8		1FF98			;

197 bytes



## APPENDIX I

### SERIAL COMMUNICATIONS CONTROLLER TEST PGM

First, memory is loaded with the arbitrary character "A." Then the SCC is initialized. The CPU then goes into a loop where it puts out the "A" from memory to the SCC Tx buffer and checks to see if the Tx buffer is empty. It keeps polling the Tx buffer until it is empty. Then the CPU fetches the "A" from memory again and the process repeats. For this test, the timer and the 8259 are not used.

The code is read from bottom to top.

8086 ADDR		LO BYTE EPROM ADDR	HI BYTE EPROM ADDR	
FFFF4	FF	1FFFA		;Jump to FFFA5
FFFF3	F0		1FFF9	;to begin program
FFFF2	00	1FFF9		;
FFFF1	A5		1FFF8	;
FFFF0	EA	1FFF8		; <---(Pwr on rst jmp)
FFFEF	FF		1FFF7	;Jump to read character
FFFEF	F0	1FFF7		;from memory again
FFFEF	00		1FFF6	;(Tx buffer empty)
FFFEF	CD	1FFF6		;
FFFEF	EA		1FFF5	;
FFFEA	FF	1FFF5		;Jump to read RR0 again;
FFFE9	F0		1FFF4	;Tx buffer not yet empty
FFFE8	00 (CD)	1FFF4		;(CD-->Put out the char
FFFE7	DB		1FFF3	;from memory, anyway)
FFFE6	EA	1FFF3		;
FFFE5	05		1FFF2	;If Tx buffer empty, skip
FFFE4	74	1FFF2		;next JMP statement
FFFE3	44		1FFF1	;Compare AL with #44
FFFE2	3C	1FFF1		;AL = 44 if Tx empty
FFFE1	EC		1FFF0	;Read byte in RR0-->(AL)
FFFE0	EE	1FFF0		;Tell WR0 what reg to
				;read
FFFDF	00		1FFEF	;Load AL with 00-->The reg
FFFDE	B0	1FFEF		;to be read is RR0
FFFDD	00		1FFEE	;Load DX for SCC CS* and
FFFDC	00	1FFEE		;to read (or write) a CW
FFFDB	BA		1FFED	;

The character at [40000] is put out to the SCC to be automatically transmitted at 9600 baud.

FFFDA	EE	1FFED	_____	;OUT the data ("A") to
			_____	;the SCC
FFFD9	00		1FFEC	;Load #0002 into DX for
FFFD8	02	1FFEC		;SCC CS* and indicating
FFFD7	BA		1FFEB	;data to come instead of
			_____	;CW
FFFD6	05	1FFEB		;Move the "A" at [40000]
FFFD5	8A		1FFEA	;to AL
FFFD4	00	1FFEA		;Load DI with 00 00
FFFD3	00		1FFE9	;
FFFD2	BF	1FFE9	_____	;
FFFD1	D8		1FFE8	;Move AX to DS reg
FFFD0	8E	1FFE8	_____	;
FFFCF	00		1FFE7	;Move #4000 to AX
FFFC E	40	1FFE7	_____	;
FFFC D	B8		1FFE6	_____

The following code initializes the SCC registers for the proper baud rate and protocols.

FFFC C	EE	1FFE6	_____	;
FFFC B	03		1FFE5	;Enable baud rate gen
FFFC A	B0	1FFE5	_____	;
FFFC 9	EE		1FFE4	_____
FFFC 8	0E	1FFE4		;WR14
FFFC 7	B0		1FFE3	_____
FFFC 6	EE	1FFE3	_____	;
FFFC 5	06		1FFE2	;TC = 06
FFFC 4	B0	1FFE2	_____	;
FFFC 3	EE		1FFE1	_____
FFFC 2	0C	1FFE1		;WR12
FFFC 1	B0		1FFE0	_____
FFFC 0	EE	1FFE0	_____	;
FFFB F	16		1FFDF	;TRxC will have baud
FFFB E	B0	1FFDF		;rate out
FFFB D	EE		1FFDE	_____
FFFB C	0B	1FFDE		;WR11
FFFB B	D0		1FFDD	_____
FFFB A	EE	1FFDD		;Write WR5 with (AL)
FFFB 9	68		1FFDC	;Load AL with 68
FFFB 8	B0	1FFDC		;8 bits/char
				;Tell WR0 that WR5 is
FFFB 7	EE		1FFDB	;next
FFFB 6	05	1FFDB		;Load AL with 05
FFFB 5	B0		1FFDA	_____

FFFB4	EE		1FFDA	_____	;Write WR4 with 4C (fm
FFFB3		4C		1FFD9	;AL); Load AL with 4C-
FFFB2	B0		1FFD9	_____	;x16 Mode,2 stop bits
FFFB1	EE			1FFD8	;Load WR0 with 04 (fm AL)
FFFB0	04		1FFD8	_____	;Load AL with 04--will
FFFAF	B0			1FFD7	;write Write Reg 4 (WR4)
FFFAE	00		1FFD7	_____	;Load DX for CS* of the
FFFAD	00			1FFD6	;SCC to write a control
FFFAC	BA		1FFD6	_____	;word (CW) to Write Reg 0
					;to tell the SCC which
					;register CW will be
					;written next

Load the character "A" into memory location [40000].

FFFAB		C1		1FFD5	_____	;Write "A" to [DS + DI =
FFFAA	05		1FFD5			;40000]
FFFA9		C6		1FFD4	_____	;
FFFA8	D8		1FFD4			;Move AX to DS
FFFA7		8E		1FFD3	_____	;
FFFA6	40		1FFD3			;Move #4000 to AX
FFFA5		00		1FFD2	_____	;
FFFA4	B8		1FFD2			;

81 bytes

## APPENDIX J

### LIST OF COMPONENTS

- 2 AM27C010--128K x 8 bit EPROM
- 8 MSM8128S-12--128K x 8 bit SRAM
- 3 CD54HC573F3A--Address latch (Octal D type latch)
- 2 CD54HC245F3--Data transceiver (Octal tri-state)
- 3 CD54138F3A--3 to 8 Decoder
- 1 MC74HC32N--quad 2 input OR gate
- 1 Z85C30--SCC serial communications controller
- 1 MD82C59A-5/B--Programmable interrupt controller
- 1 MD80C86-2/B--16 bit microprocessor
- 1 MD82C85/B--Static clock controller/generator
- 1 Xtal CTS MP150 15.000--15 MHz crystal (Have also used 4.0 MHz xtal)
- 1 MC7805C--5 volt voltage regulator
- 1 MM54HC161J/883C--Synchronous binary counter with asynchronous clear
- 1 M82C53-5--Programmable interval timer
- 1 MC1488--quad line driver (+, - 9v)
- 1 MC1489A--quad line receiver(+5v)
  
- 1 82C55--programmable Peripheral interface
  
- 1 DB 25 P RS-232 connector
  - Pin 2-Trans data Tx output
  - Pin 3-Rcv data Rx input
  - Pin 7-Sig Gnd Gnd common
  
- 1 SPDT Pushbutton switch

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